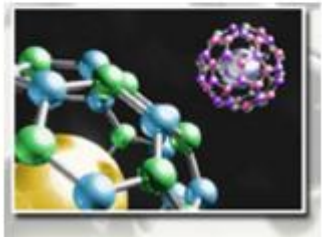




**PHYSICS and
ASTROPHYSICS**



**CHEMICAL and
MATERIAL SCIENCES**

Ion Beam Based Techniques for Materials Science

Teachers:

Paolo Olivero, Ettore Vittone

Physics Department, University of Torino

www.solid.unito.it

2 CFU : 8 h

Tuesday 2.5.2017, h. 16-18, Aula Verde, Physics Dept. - Ettore Vittone

Wednesday 3.5.2017, h. 16-18, Aula Wick, Physics Dept. - Ettore Vittone

Thursday 4.5.2017, h. 16-18, Aula D, Physics Dept. - Paolo Olivero

Friday 5.5.2017, h. 16-18, Aula Verde, Physics Dept. - Paolo Olivero

CAMPUSNET WEB SITE:

http://dott-scm.campusnet.unito.it/do/corsi.pl/Show?_id=j56m

Final exam:

Brief seminar (15 min) on a topic relevant to Ion Beam Based Techniques

Introduction

These lectures will deal with

Ions → Charged particles

Light ions (^1H and ^4He)

MeV light ions

MeV light ions currents/fluxes/fluences

Ion energy (E) → $E=e \cdot V$ → electrostatic accelerator

Example:

12 MV accelerator voltage

$E(^1\text{H}^+) = 12 \text{ MeV}$

$E(^4\text{He}^{++}) = 24 \text{ MeV}$

Ion current: $I=Q/t$; $Q=\text{charge}=N_{\text{ion}} \cdot e \cdot n$; ($n=\text{ion charge state}$)

Ion flux: $\Phi=N/t \cdot A$; $A=\text{unit area}$

Ion Fluence: $F=\int_0^t \Phi dt$

Example:

$I=1 \text{ pA}$

If $^1\text{H}^+$: $n=1$; $10^{-12}/1.6 \cdot 10^{-19} \text{ ions/s} = 6 \cdot 10^6 \text{ ions/s}$

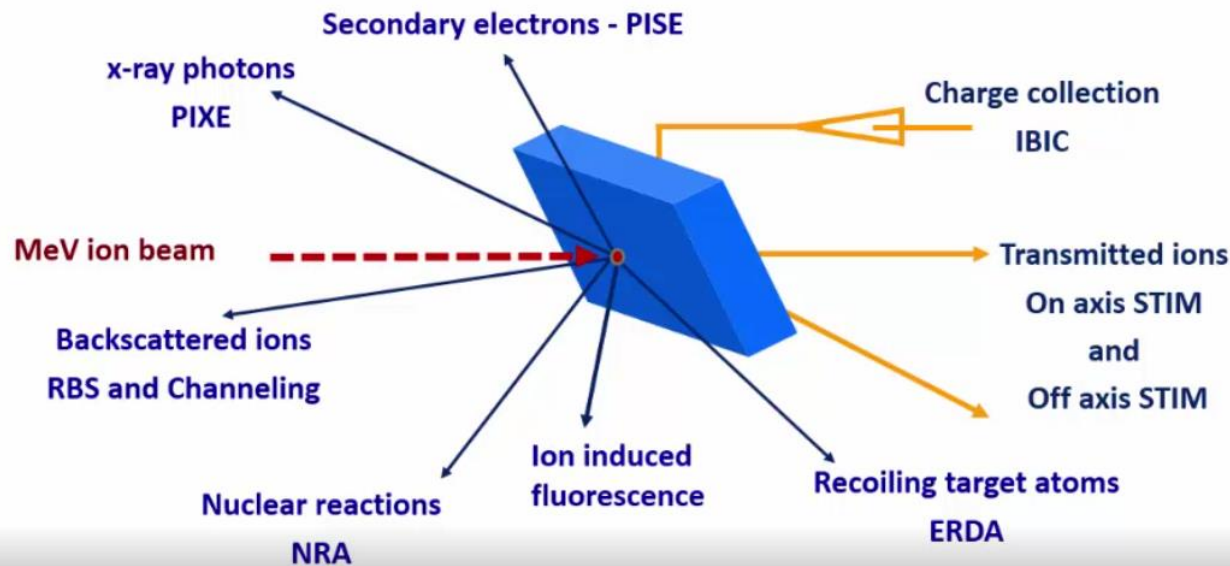
If $^4\text{He}^{++}$: $n=2$; $2 \cdot 10^{-12}/1.6 \cdot 10^{-19} \text{ ions/s} = 12 \cdot 10^6 \text{ ions/s}$



From the many interactions that MeV ion beams create in a sample

we can **extract information** on the structure/composition/functionality of the material

Ion Beam Analysis



<http://www.ciba.nus.edu.sg/pages/gallery.html>

we can **modify** the structure/composition/functionality of the material

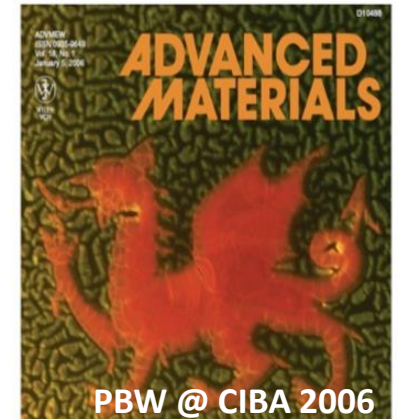
Ion Beam Material Modification

Ion micromachining

Defect Engineering

Deep Ion Beam Lithography

Proton Beam Writing



Introduction

Accelerators

Instrumentation

Ion sources

Detectors

**Ion-Solid
interaction**

Electronic energy loss

Nuclear energy loss

IBA techniques

Compositional analysis

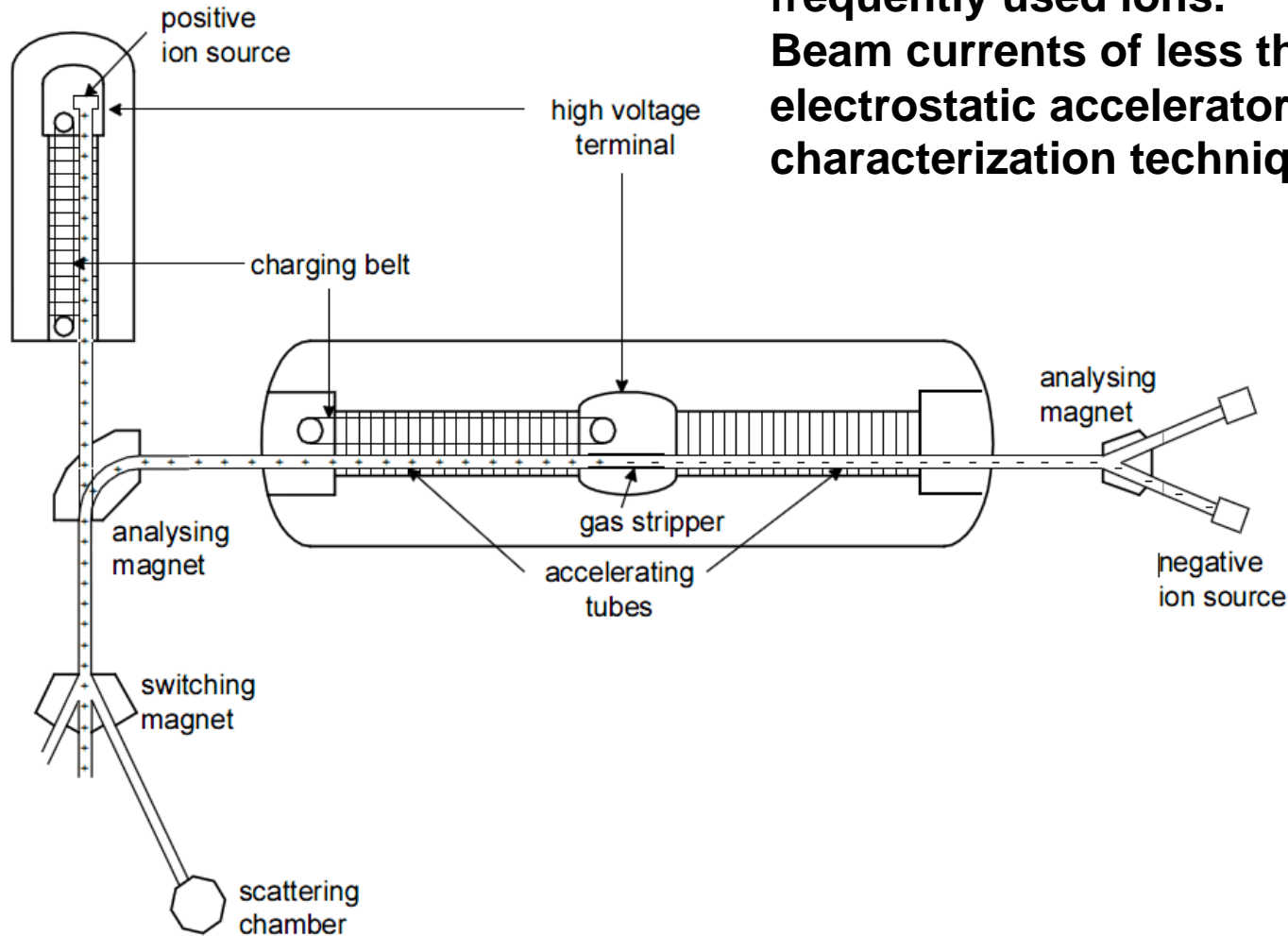
Structural analysis

Functional analysis

Instrumentation

The most common type of accelerators used for the application of ion beam analysis Techniques are the **electrostatic accelerators**. Protons and alpha in the energy range 1–3 MeV are the most frequently used ions.

Beam currents of less than 1 μA (easily delivered by the typical electrostatic accelerator) are sufficient for all existing characterization techniques.

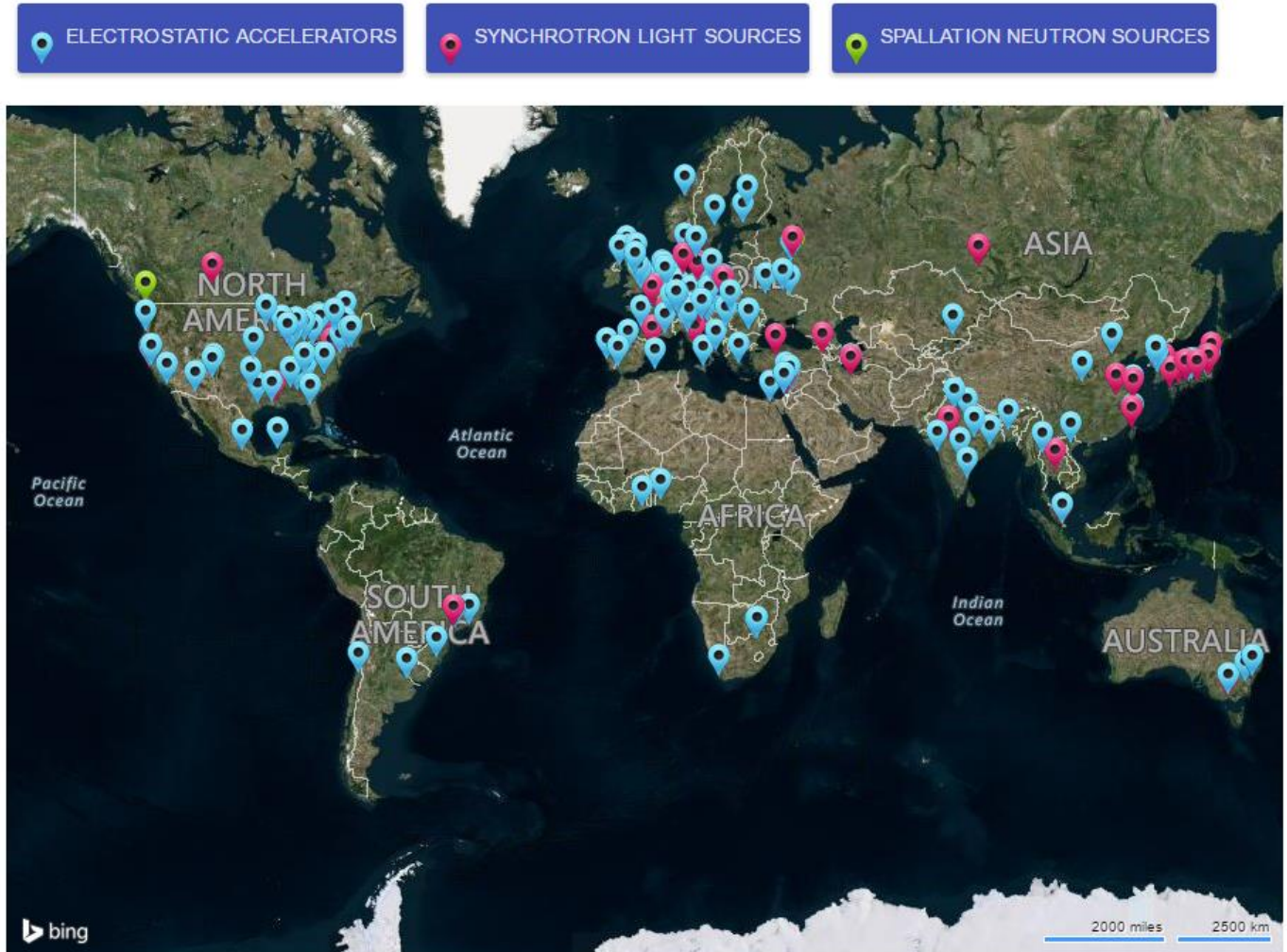


Instrumentation for PIXE and RBS; IAEA-TECDOC-1190

<http://www-pub.iaea.org/books/iaeabooks/5966/Instrumentation-for-PIXE-and-RBS>

<https://nucleus.iaea.org/sites/accelerators/Pages/default.aspx>

**More than 200 ion beam
facilities in the world**



Instrumentation

92 ion beam facilities in Europe-Ukraine- Russia-Israel



ELECTROSTATIC ACCELERATORS



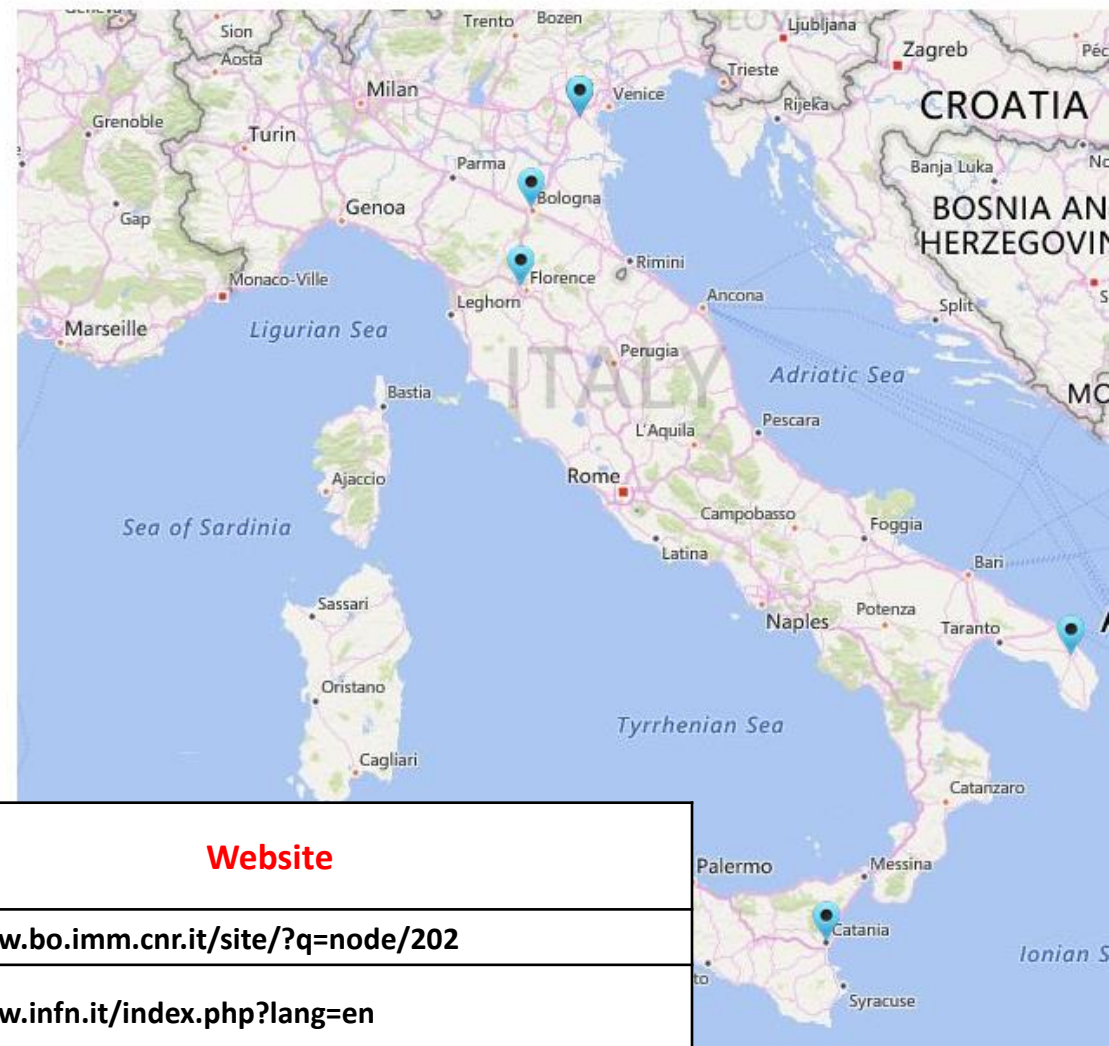
SYNCHROTRON LIGHT SOURCES



SPALLATION NEUTRON SOURCES

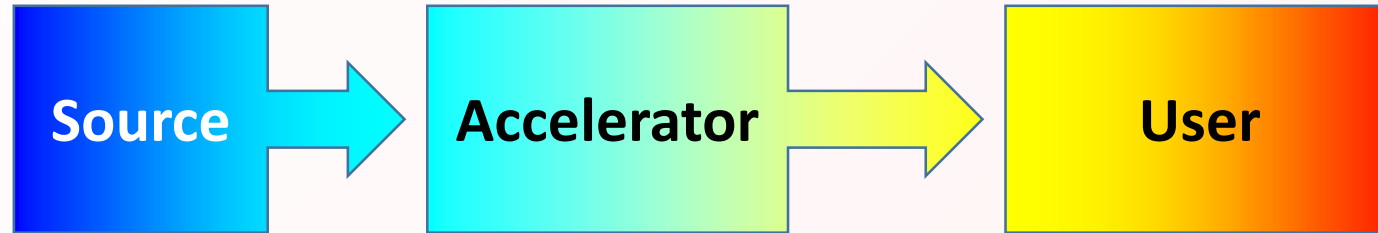


5 ion beam facilities in Italy



Facility Name	City	Accelerator Type	Accelerator Description	Terminal Voltage (kV)	Website
CNR-IMM	Bologna	Tandem	Other	1700	http://www.bo.imm.cnr.it/site/?q=node/202
INFN-Instituto Nazionale di Fisica Nucleare	Florence	Tandem	Dynamitron	3000	http://www.infn.it/index.php?lang=en
INFN.Laboratori Nazionali di Legnaro	Legnaro	Single-ended Single-ended Tandem	Van de Graaff Van de Graaff Other	7000 2500 15000	http://www.lnl.infn.it/accelerators/accelerators.html
University of Catania	Catania	Single-ended	Dynamitron	3100	http://www.unict.it/en/
University of Lecce	Lecce	Tandem	Dynamitron	3000	http://www.unisalento.it/web/guest/home_page

Schematic View of the principal component of an ion accelerator system



A **source of charged particles**

Accelerating elements

Electrostatic column which provide the electric fields giving the energy to the ions

Beam guiding elements,

mainly magnetic, in order to maintain (focus) the beam on the wanted trajectory

Ancillary systems:

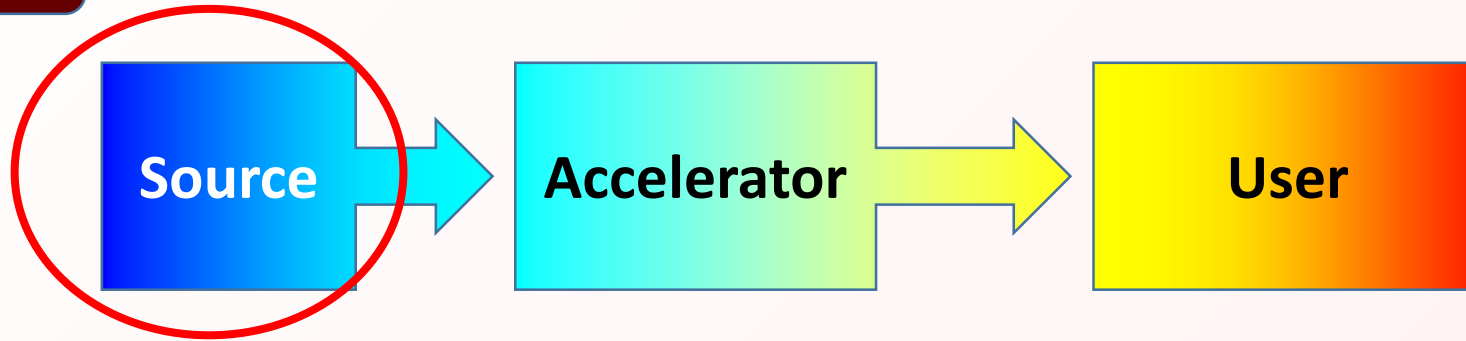
High vacuum is needed to avoid perturbation of the beam by collisions with residual gas

Beam diagnostics assure the monitoring of the beam trajectories

User installation

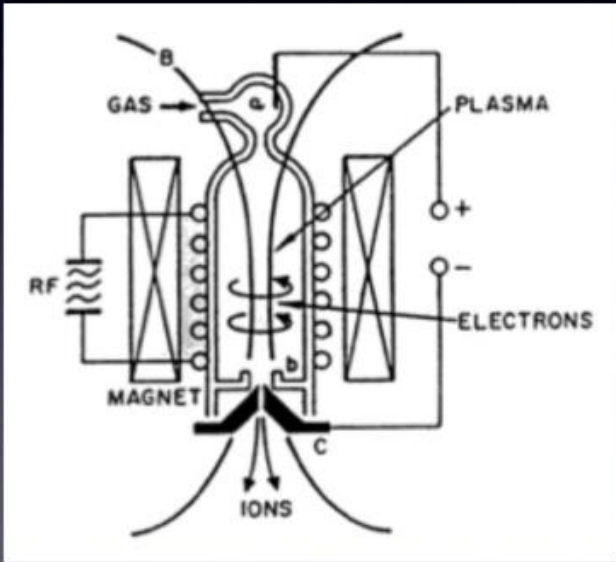
Experimental set-ups including
Targets, spectrometers, detectors

Schematic View of the principal component of an ion accelerator system



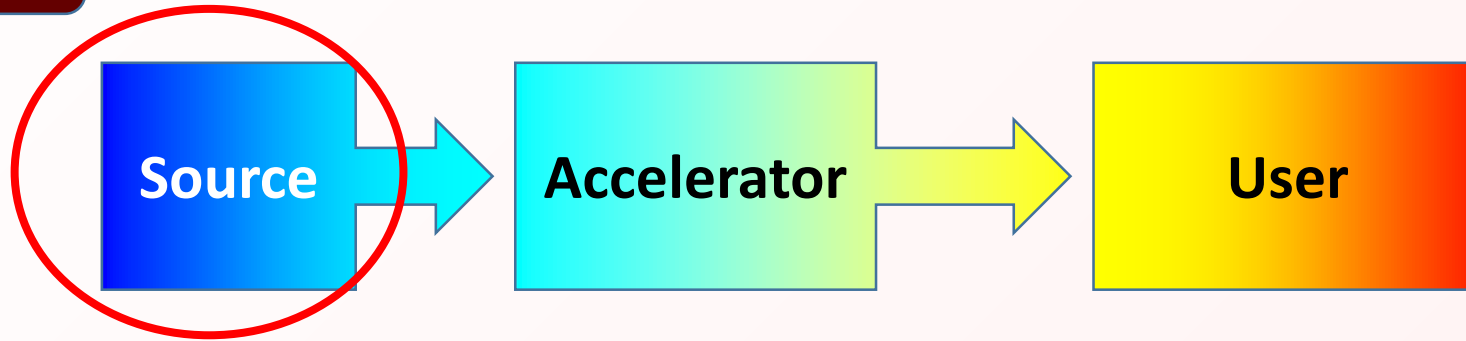
Positive ion: RF ion source

- The **RF** (Radio Frequency) **ion source** is a bottle which contains a gas (typically $^1\text{H}_2$ or ^4He), which is excited by an RF oscillator capacitive coupled to the bottle.
- The plasma is confined and positioned by an axial magnetic field.
- A small positive bias voltage across the ion source bottle propels the positive ions out through the canal.
- Typically 10 μA beam current
- Longevity of the source used in single ended machine



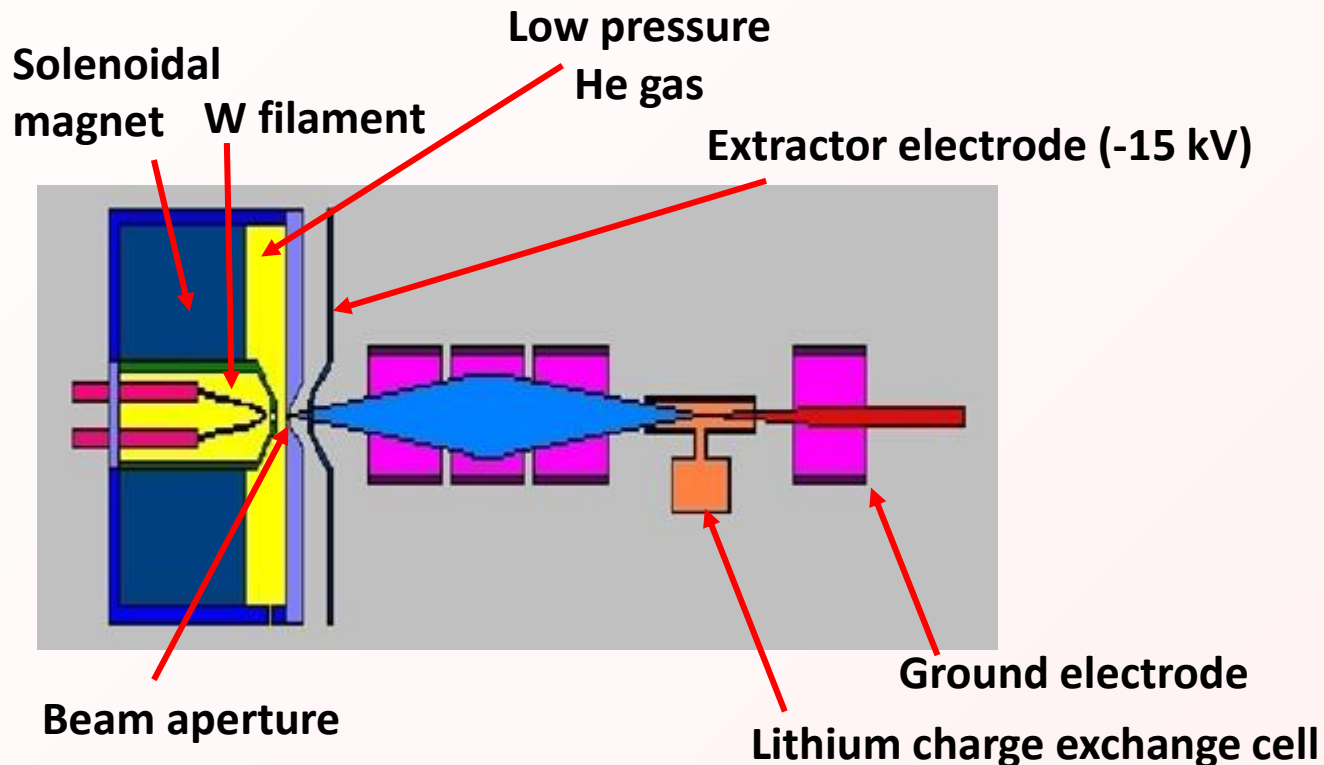
High Voltage Engineering
Europa B.V

Schematic View of the principal component of an ion accelerator system

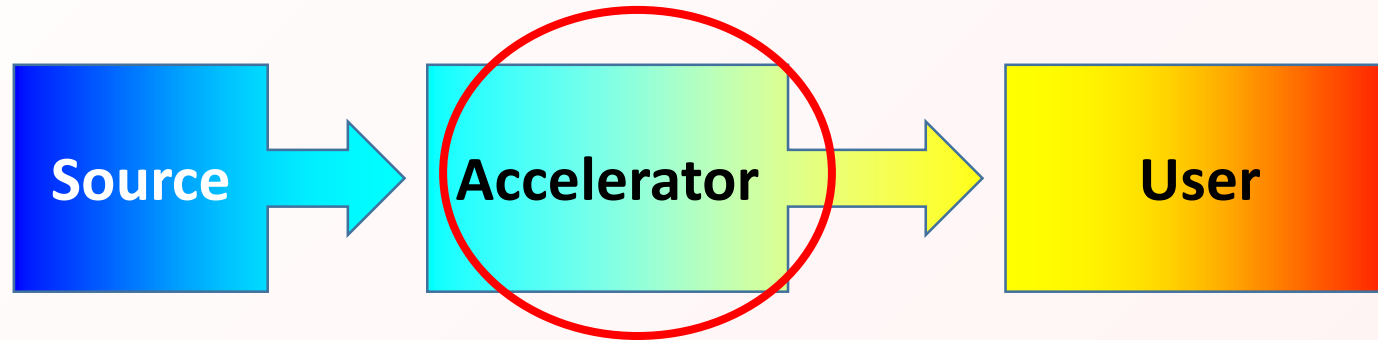


Negative ion: Duoplasmatron ion source

- Positive ions are generated by ionization induced by electrons produced by thermoionic emission from hot W filaments. A plasma is then generated and confined by a solenoidal magnetic field.
- The positive ions are accelerated by the extractor electrode.
- The positive ions are focused into a cell where metal Li (or Rb) is heated to form a vapor.
- The Li vapor charge exchanges with the positive ions, giving up electrons to the beam particles.
- Negative ions are accelerated out of the charge exchange cell.
- Positive ion current: $100\ \mu\text{A}$ → Negative ion production efficiency: 2%

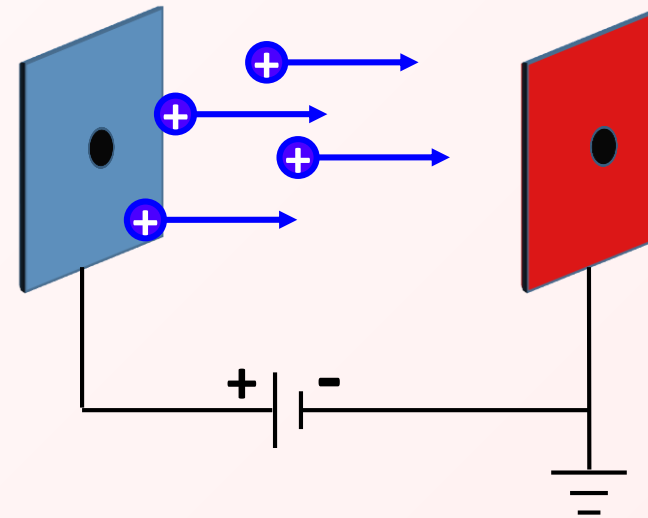


Schematic View of the principal component of an ion accelerator system



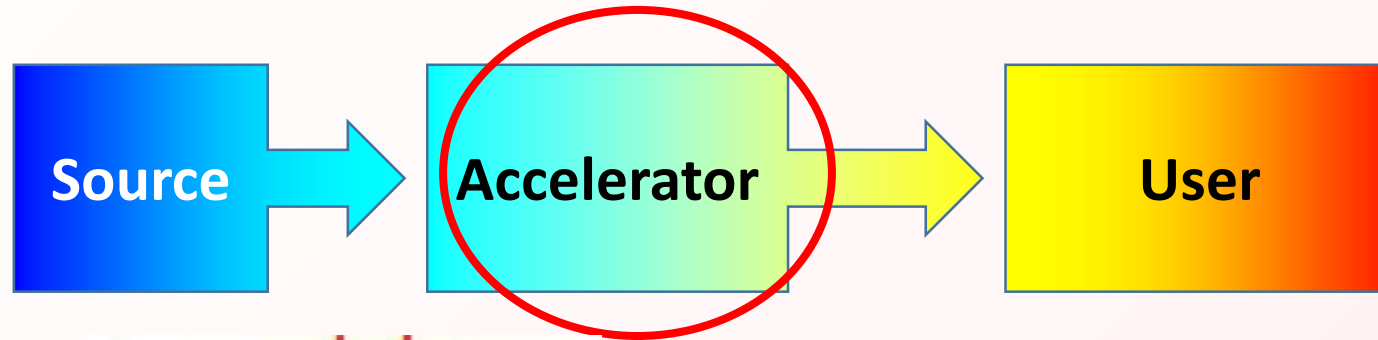
Accelerating elements

- ✓ Electrostatic column which provide the electric fields giving the energy to the ions
- ✓ An ion source injects the charged particles
- ✓ Between the entry and the exit, a continuous high voltage is applied, mediated by intermediate electrodes for a smooth and regular increase of the electric field

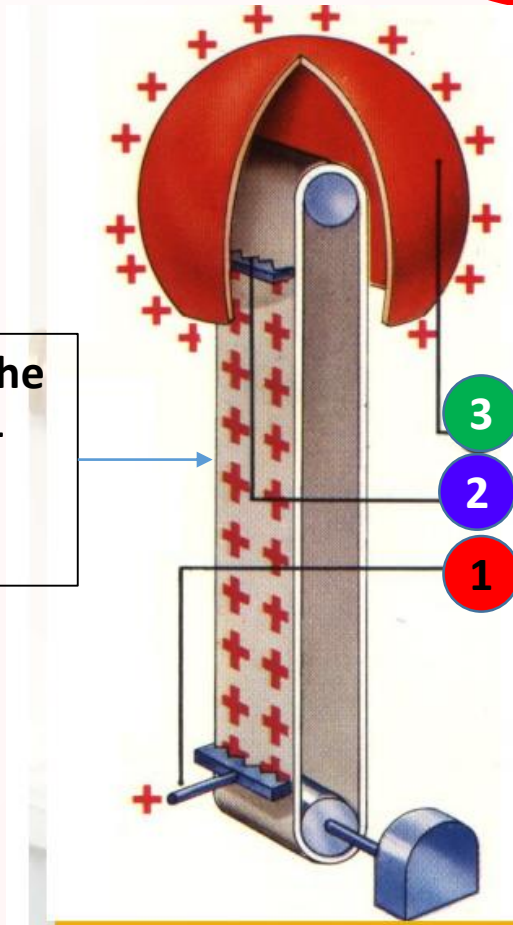


A.C. Mueller, IAEA School on ADS, Trieste, 19-30/10/2007

Schematic View of the principal component of an ion accelerator system



The conveyor transports the charges inside the sphere-shaped terminal, which forms a Faraday cage

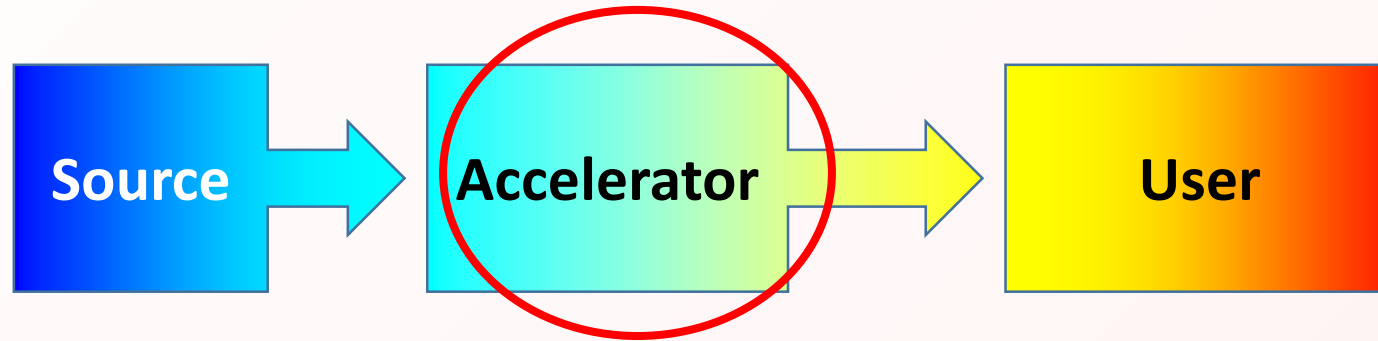


High voltage for electrostatic acceleration
(Van de Graaff method)

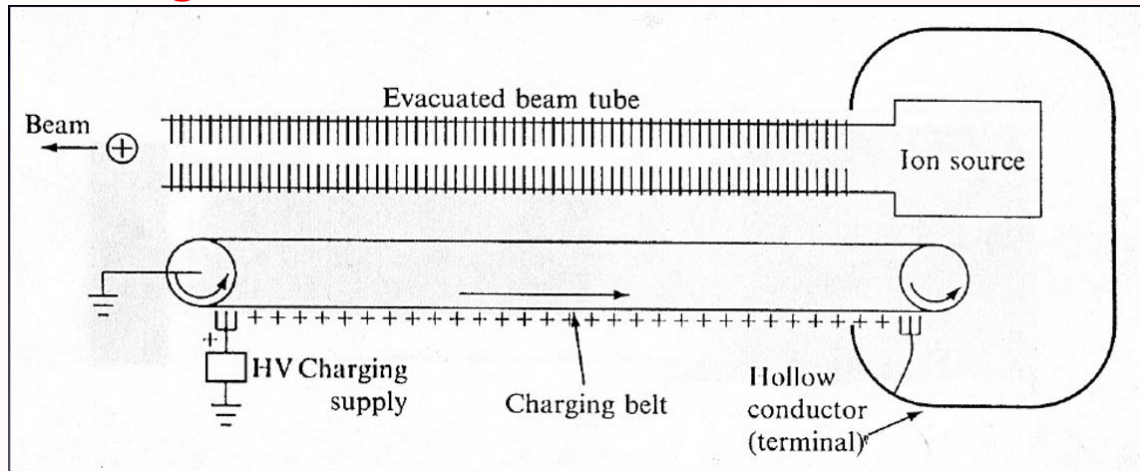
- 1 A comb-like electrode sprays charges on an insulating conveyor belt
- 2 The charges are collected by a second, comb-like electrode, which is connected to the sphere
- 3 The charges accumulate on the outside of the sphere and the inside get charge free, ready to accept further charging

In practice, one can reach up to 25 MV, provided one uses SF₆ gas for limiting breakdowns

Schematic View of the principal component of an ion accelerator system



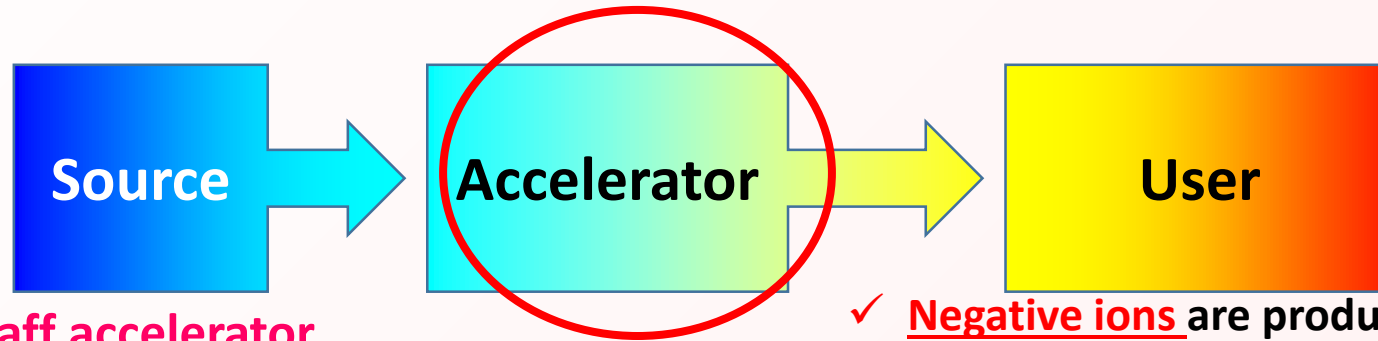
Single ended Van de Graaff accelerator



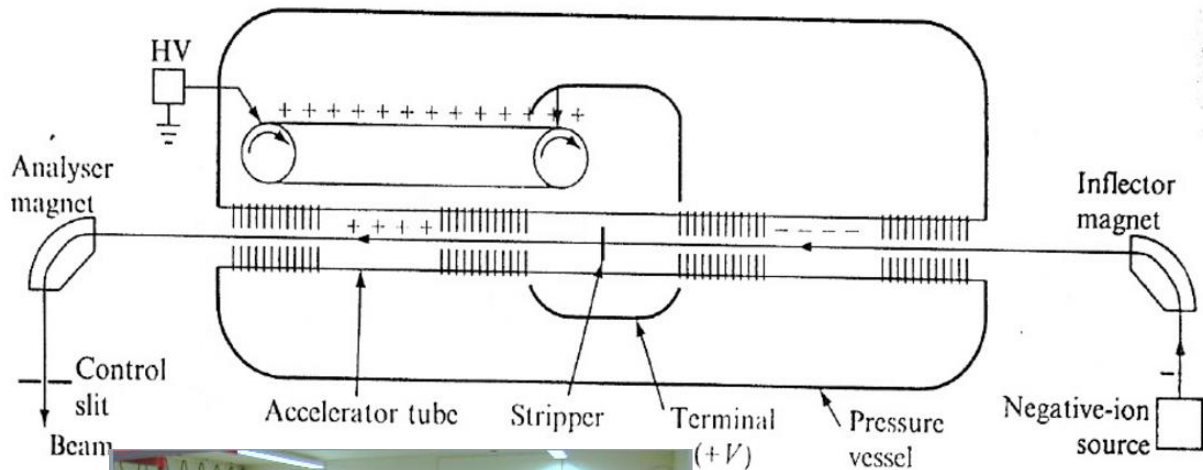
The **positive ion** source is inside the high voltage terminal
The voltage is distributed uniformly between the terminal and the ground by a chain of high voltage resistors.
The chain operates inside a **vessel**, pressurized with an insulating gas (SF₆) to aid in reducing ionization and arc-over.



Schematic View of the principal component of an ion accelerator system



Tandem Van de Graaff accelerator



Bochum

- ✓ **Negative ions** are produced at ground potential and accelerated to the positive terminal located midway along the tube structure.

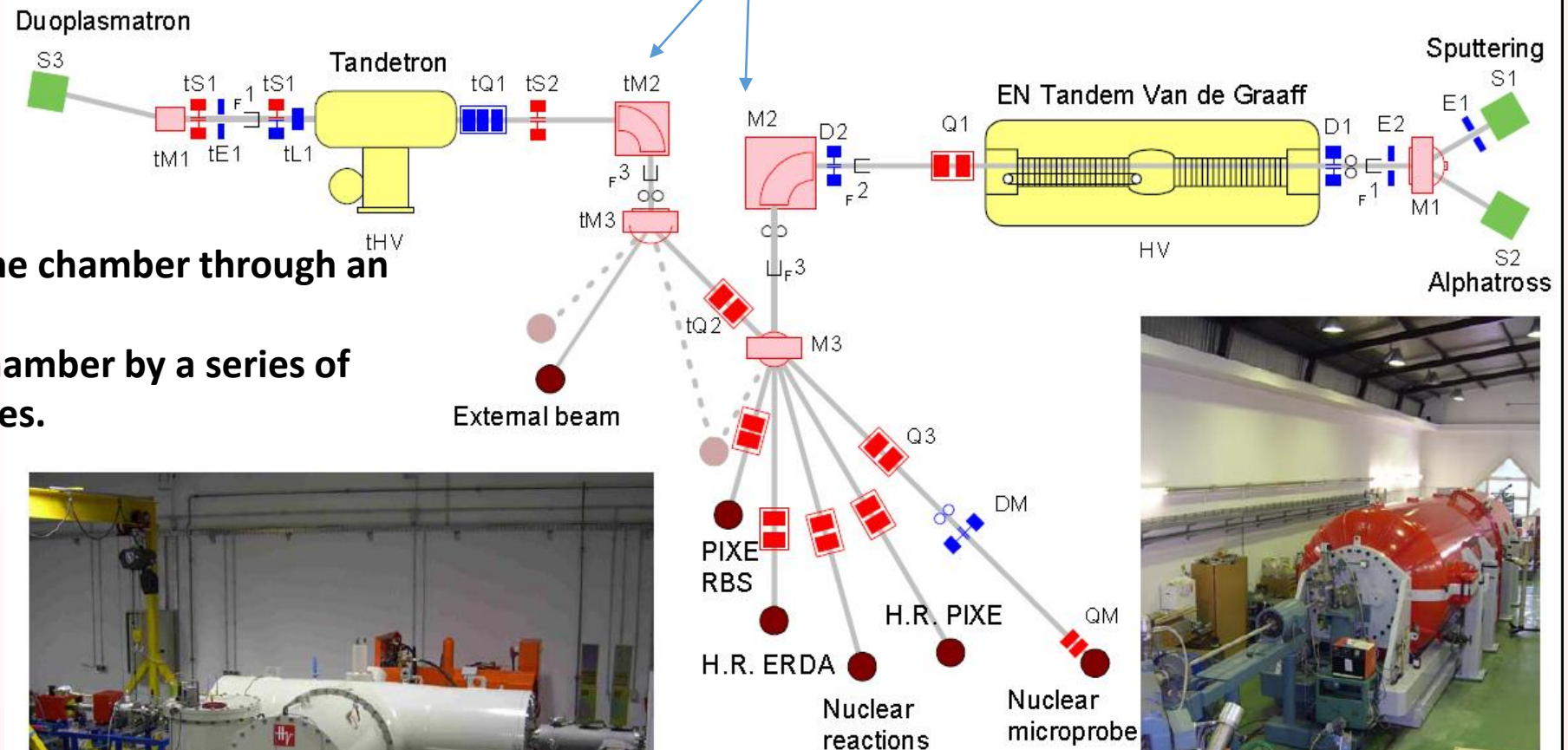


Source not inside the terminal



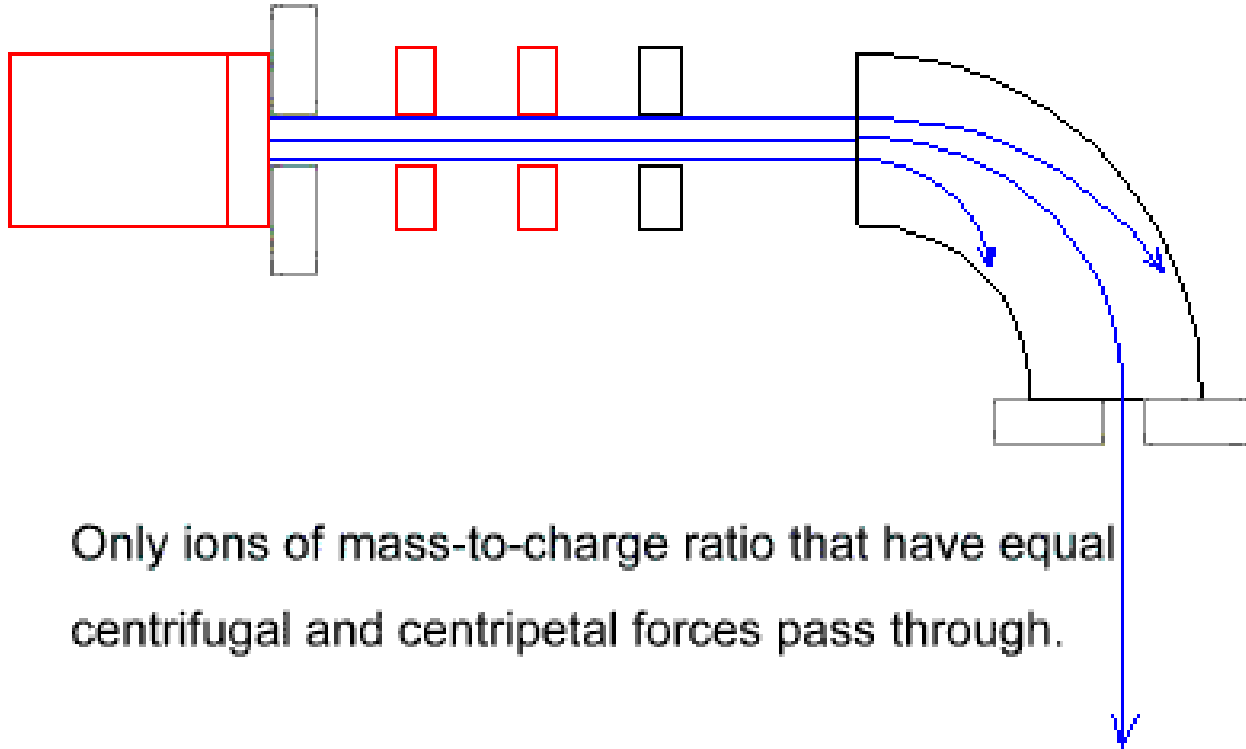
- ✓ Limited range of ion available
- ✓ Inside the terminal, ions encounter either a thin carbon foil or tenuous gas (typically N₂).
- ✓ Ions are stripped of electrons through collisions within the stripper region and emerge with positive charge.
- ✓ Because the terminal is positive, they are further accelerated.
- ✓ The total energy they acquire is $(n+1)V$, where n is the final charge state of the ions and V is the terminal voltage.
- ✓ Tandem accelerators can produce ion beams that are far more energetic than those available from single ended accelerators.

Analyzing magnets



... and 2 accelerators





Only ions of mass-to-charge ratio that have equal centrifugal and centripetal forces pass through.

Filters the ions by the momentum per unit charge or, equivalently, by the magnetic rigidity

B = magnetic induction

M = particle mass

E = particle energy

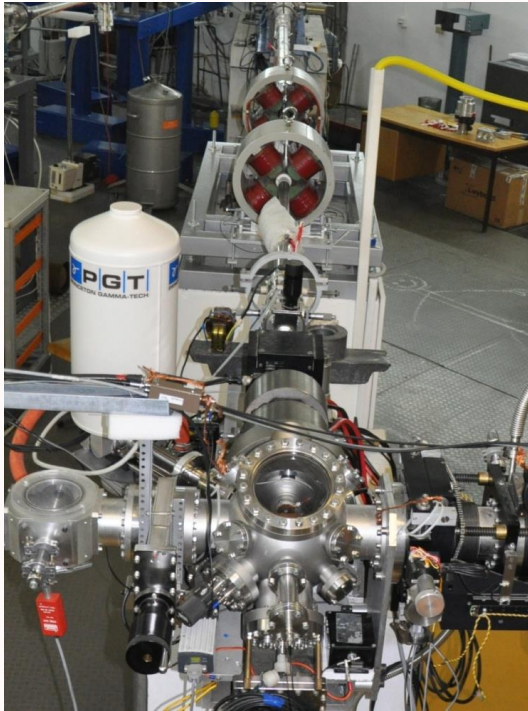
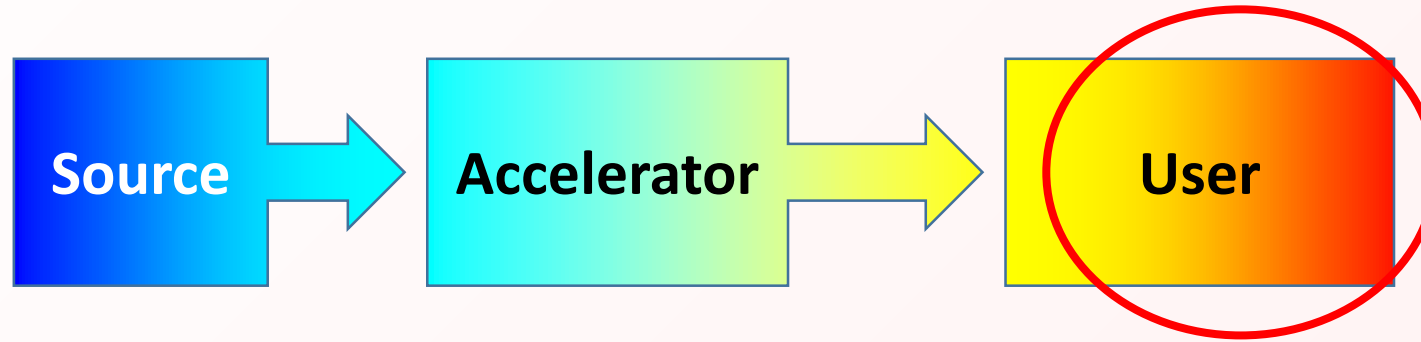
e = particle charge

R = magnet radius of curvature

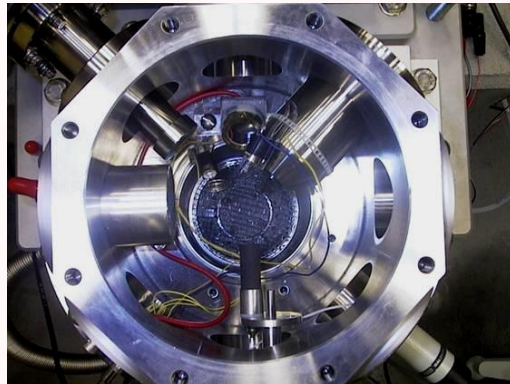
$$B \cdot R = \sqrt{\frac{2ME}{e^2}}$$

<http://www.casetechnology.com/implanter/magnet.html>

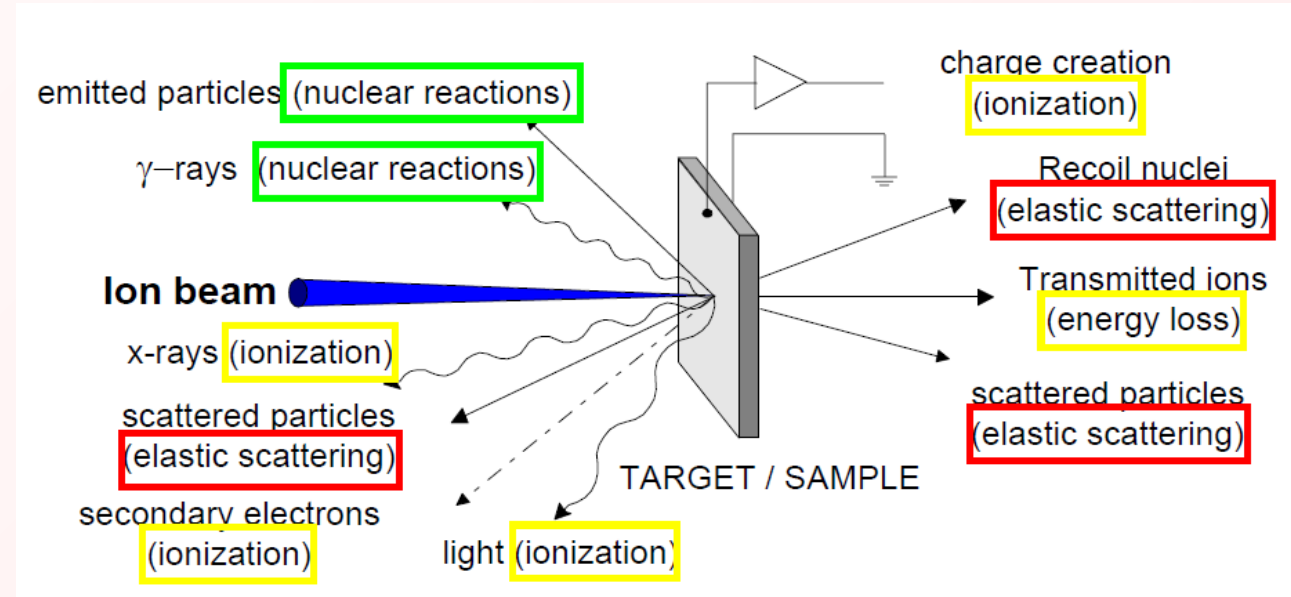
Schematic View of the principal component of an ion accelerator system



Ruder Boskovic Institute,
Zagreb (HR)



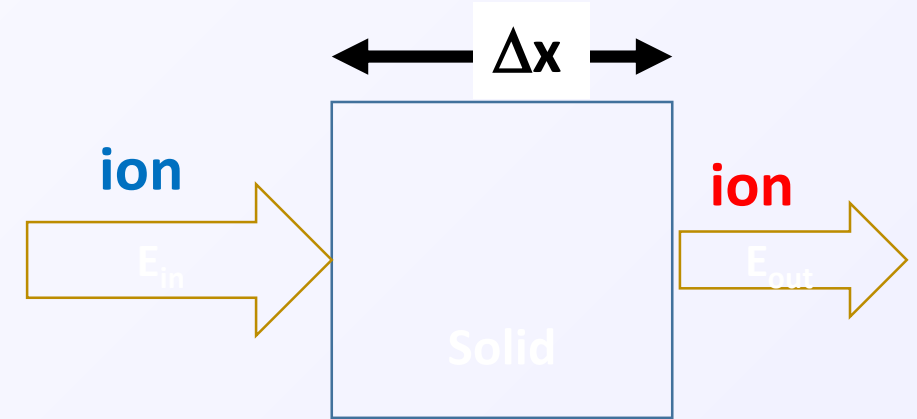
Centro Nacional de
Aceleradores, Sevilla (E)



Many interactions → different detection techniques and instrumentation

Basic concepts

The incoming ion interacts with the atoms in the target and loses energy via collisions with atomic electrons and nuclei
Energy transfer -> ion slowing until they come to rest at some depth in the material



Energy loss per distance Δx traversed: $\Delta E = E_{in} - E_{out}$

Stopping Power or Specific Energy Loss: $S = \lim_{\Delta x \rightarrow 0} \left(\frac{\Delta E}{\Delta x} \right) = \frac{dE}{dx}$

Units: $\left(\frac{keV}{\mu m} \right)$

Mass Stopping Power or Linear Energy Transfer: $LET = \frac{1}{\rho} \frac{dE}{dx}$ (ρ = mass density)

Units: $\left(\frac{MeV \cdot cm^2}{g} \right)$

Stopping Cross section : $\epsilon = \frac{1}{N} \frac{dE}{dx}$ (N = atomic density)

Units: $\left(\frac{eV}{10^{15} atoms/cm^2} \right)$

Example: Si; $M_m = 28$ g/mol; $\rho = 2.3$ g/cm³; $N = N_A \cdot \rho / M_m = 5 \cdot 10^{22}$ atoms/cm³

3 MeV He ions:

$$S = 200 \frac{keV}{\mu m} ; S_M = 858 \frac{MeV \cdot cm^2}{g} ; \epsilon = 40 \frac{eV}{10^{15} atoms/cm^2}$$

Ion-solid interaction

- ✓ The fundamental physics of the interactions between incident ions and individual atoms in the solid provides the underlying science for Ion Beam Analysis.
- ✓ Focus on 1-10 MeV ^1H and ^4He ions, which are the ions most commonly used for analytical methods.
- ✓ The most relevant features are the ways in which MeV ions lose their energy in collisions (energy loss mechanisms).

Radius of atomic nucleus: $r \sim r_0 \cdot A^{1/3}$; $r_0 \sim 1.4 \text{ fm}$
Example: $r_{\text{Si}} = 4.3 \text{ fm}$

Bohr radius: $a_0 = 52910 \text{ fm}$
Si atomic radius: $a_{\text{Si}} = 111000 \text{ fm}$
Si lattice constant: $d_{\text{Si}} = 543100 \text{ fm}$

Electronic stopping power

Slowing down of a projectile ion due to the inelastic collisions between bound electrons in the medium and the ion moving through it

- ✓ **Infrequent collision between ion and nucleus**
- ✓ Most of the energy of the MeV ion is lost in collision with electrons
- ✓ Electron energy loss is the process that determines the distance ions travel before they come to rest

Nuclear stopping power

Due to elastic collisions between the projectile ion and atomic nuclei in the sample. The interaction is the electrostatic repulsion between the incoming charged ion and the positive nucleus (not the strong nuclear force).

Electronic Energy Loss Regime

E = Ion energy

$$v = \text{Ion velocity} = \sqrt{\frac{2 \cdot E}{M_{\text{Ion}}}}$$

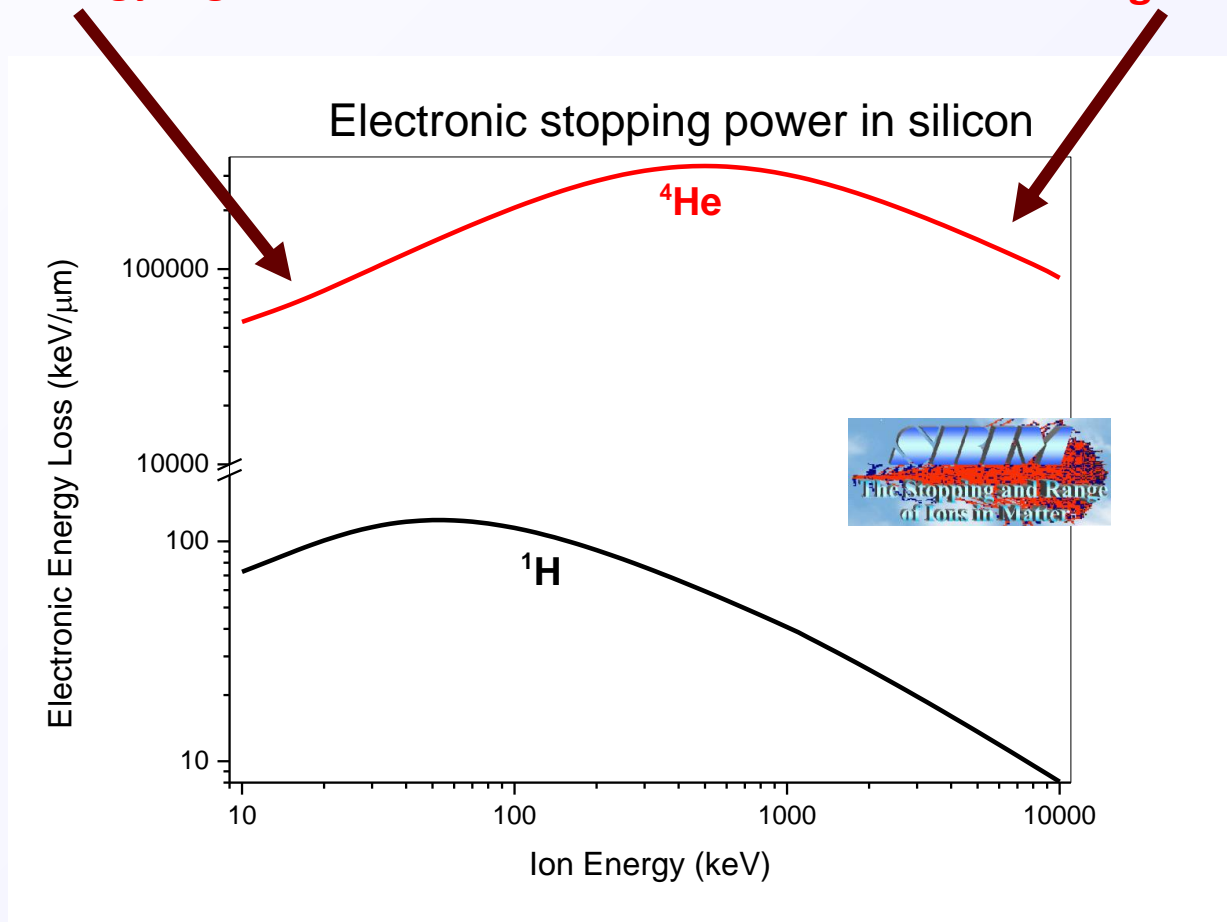
$$v_{\text{low}} < v_{\text{Bohr}} = \frac{e^2}{4\pi\epsilon_0\hbar} = \alpha \cdot c \sim 2.2 \cdot 10^6 \frac{m}{s} < v_{\text{High}}$$

$$E_{\text{low}}(^1\text{H}) < \frac{1}{2} M(^1\text{H}) \cdot (v_{\text{Bohr}})^2 = 25\text{keV} < E_{\text{High}}(^1\text{H})$$

$$E_{\text{low}}(^4\text{He}) < \frac{1}{2} M(^4\text{He}) \cdot (v_{\text{Bohr}})^2 = 100\text{keV} < E_{\text{High}}(^4\text{He})$$

Low energy regime:

High energy regime



Electronic Stopping Power: High Energy regime

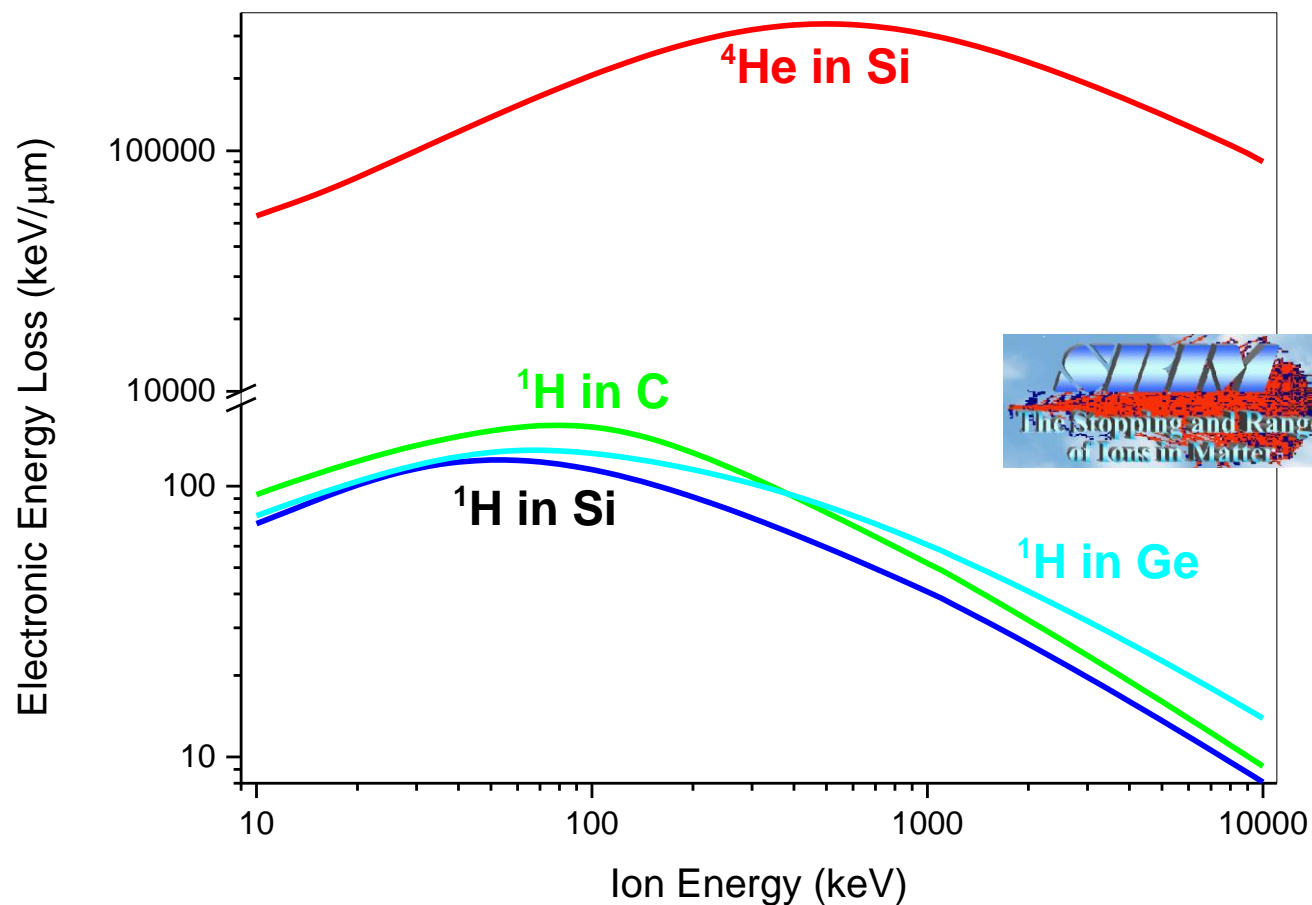
$v_{\text{Ion}} > v_{\text{Bohr}} \sim$ electron velocities in their atomic shells \longrightarrow Atoms appear static to the ions

Stripping of electrons

Fully ionized particle with a positive charge

The rate of energy loss decreases with increasing energy because the ion pass through the orbiting electron clouds faster and have less chance of interacting with them

Electronic stopping power is:
Proportional to electron density
Inversely proportional to ion kinetic energy



Ion-solid interaction

Electronic Stopping Power: Low Energy regime

$v_{\text{Ion}} < v_{\text{Bohr}} \sim$ electron velocities in their atomic shells

Atoms appear no more static to the ions

Incomplete stripping of electrons

Partially ionized particle

The rate of energy loss **increases with increasing energy**

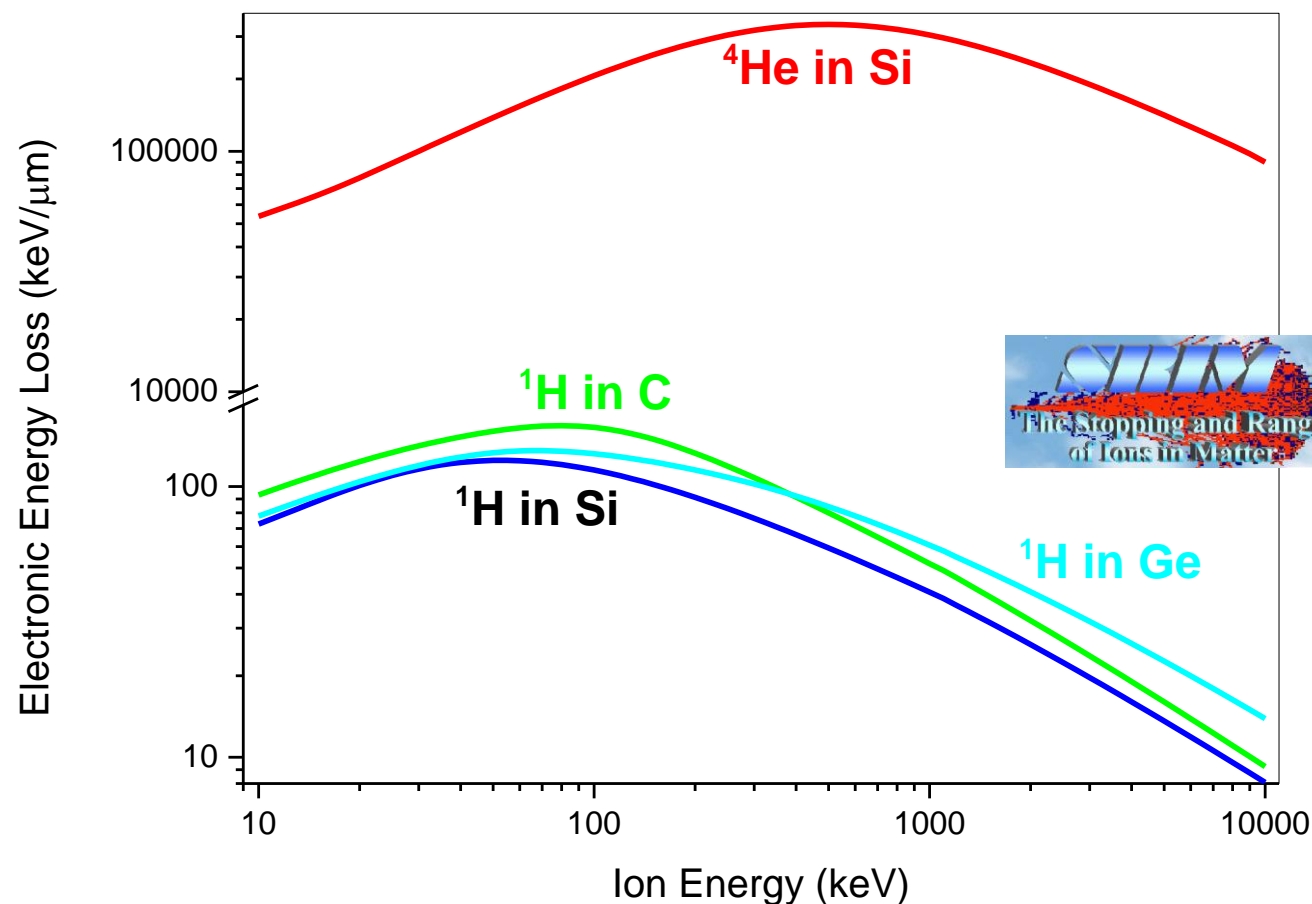
The type of interaction and the rate of energy loss **depends on the chemical nature of the target**

The maximum rate of ion energy loss occurs at the Thomas-Fermi ion velocity

$$v_{\text{TF}} = v_{\text{Bohr}} \cdot Z^{2/3}$$

$$v_{\text{TF}}(^4\text{He}) = 250 \text{ keV}$$

Inner shell electrons of the target have a declining role in energy loss



Bethe-Bloch theory

$$S = \frac{e^4}{4\pi\epsilon_0^2 m_e} \cdot \left(\frac{Z_{Ion}}{v_{Ion}} \right)^2 Z_{Target} \cdot N_{at} \cdot L(\beta)$$

$Z_{target} \cdot N_{at}$: Electron density of the target

m_e : electron mass;

ϵ_0 : vacuum dielectric constant;

e : elementary charge

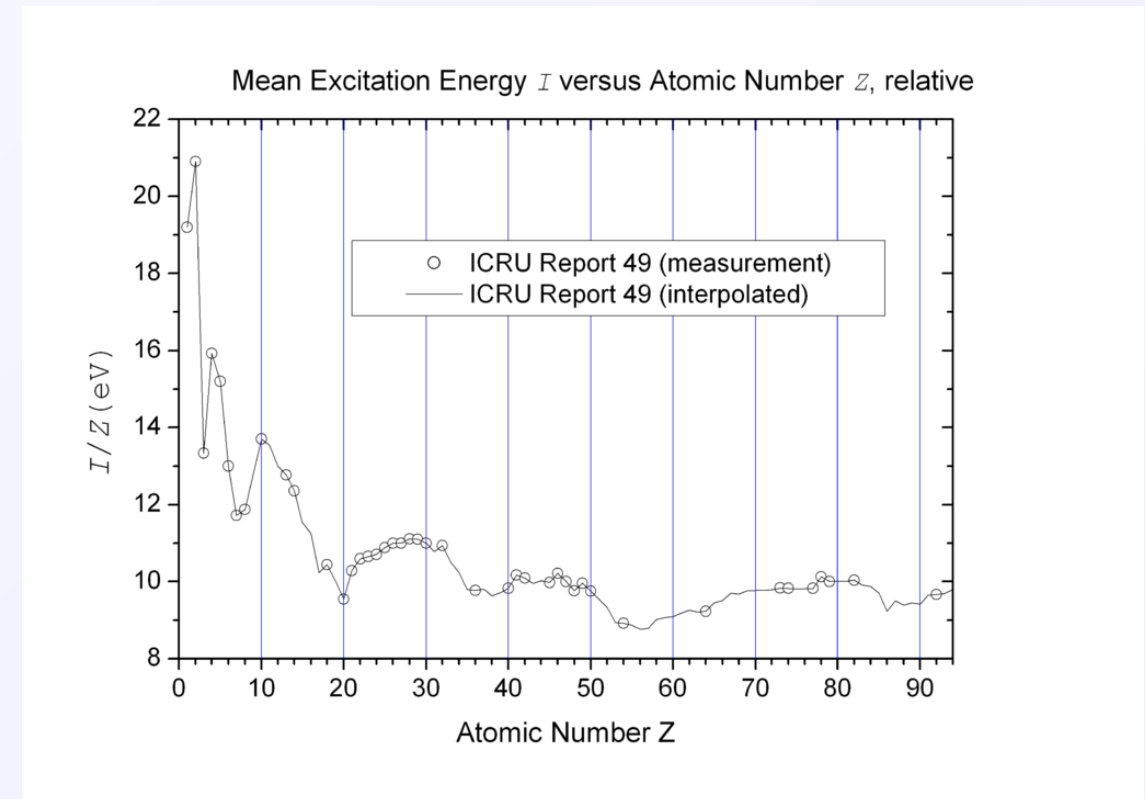
$$\frac{e^4}{4\pi\epsilon_0^2 m_e} = 4.57 \text{ MeV} \cdot \mu\text{m}^2$$

The factors preceding L take into account the gross features and L takes into account fine details.

First approximation: $L(\beta) = \ln \left(\frac{2m_e v_{Ion}^2}{I} \right)$

$I \approx 10 \cdot Z_{Target}$: average electron excitation energy

Other corrections for relativistic terms at high ion energy
and for strongly bound inner electrons



Example of the validity of the Bethe-Bloch theory:

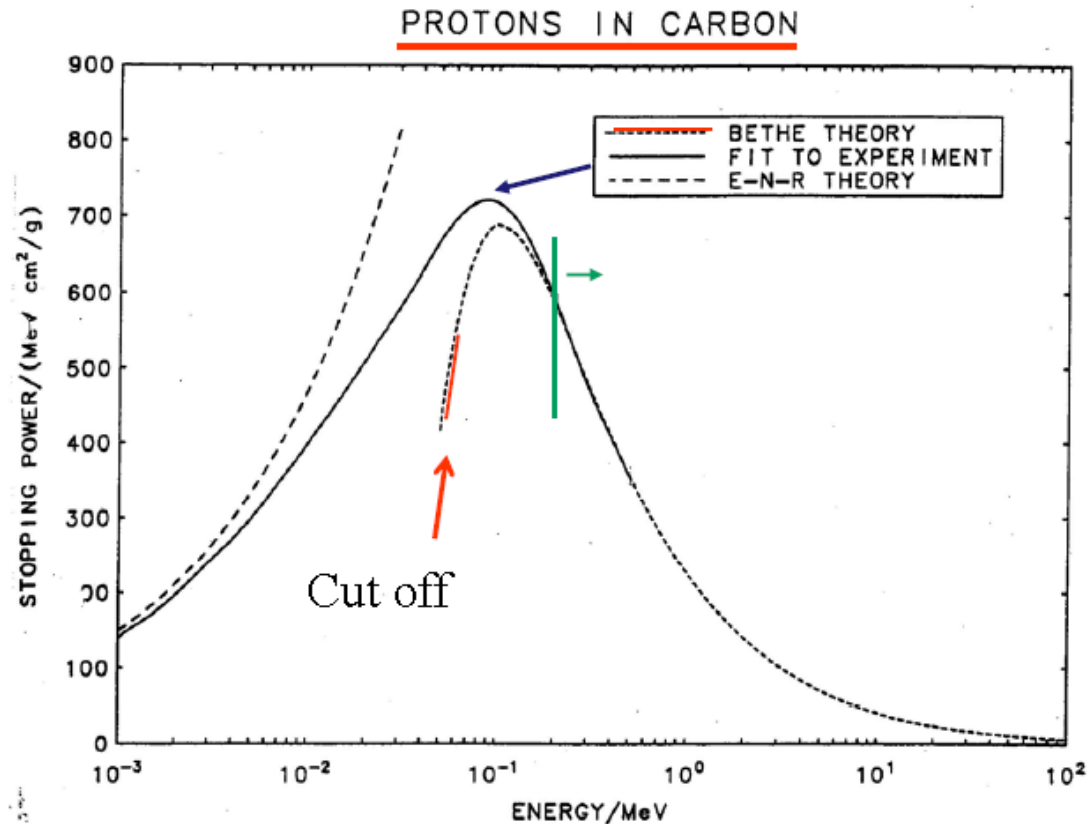


Fig. 3.10. Stopping power of amorphous carbon for protons. The short-dashed curve is from Bethe's theory, and the long-dashed curve ENR from the theory of Echenique *et al.* (1986). The solid curve is that adopted in the present work.

The large scatter in experimental results is a problem.

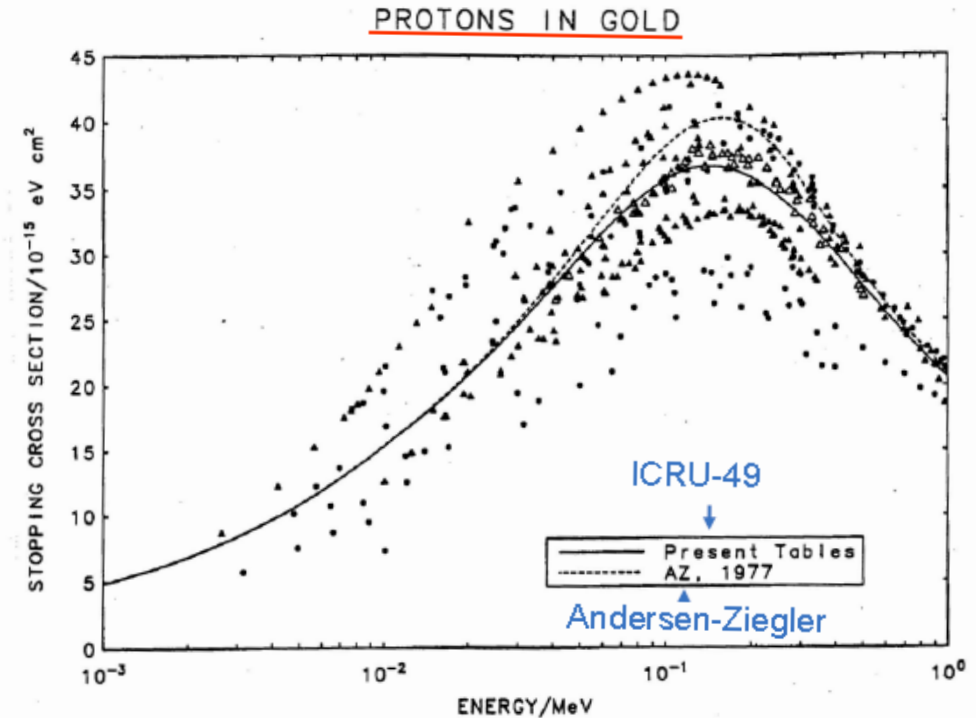


Fig. 3.2. Electronic stopping cross section of gold for protons. Experimental values are indicated by circles and triangles. Circles represent values from papers published before 1978, and triangles from papers published in 1978 or later. Hollow triangles are experimental results of the Linz-Berlin collaboration (Semrad *et al.* 1986a). Experimental values were obtained from a compilation currently in preparation by Paul *et al.* (1991). Dashed curve represents cross section from fitting formula of Andersen and Ziegler (1977), and solid curve represents stopping cross section adopted in present work.

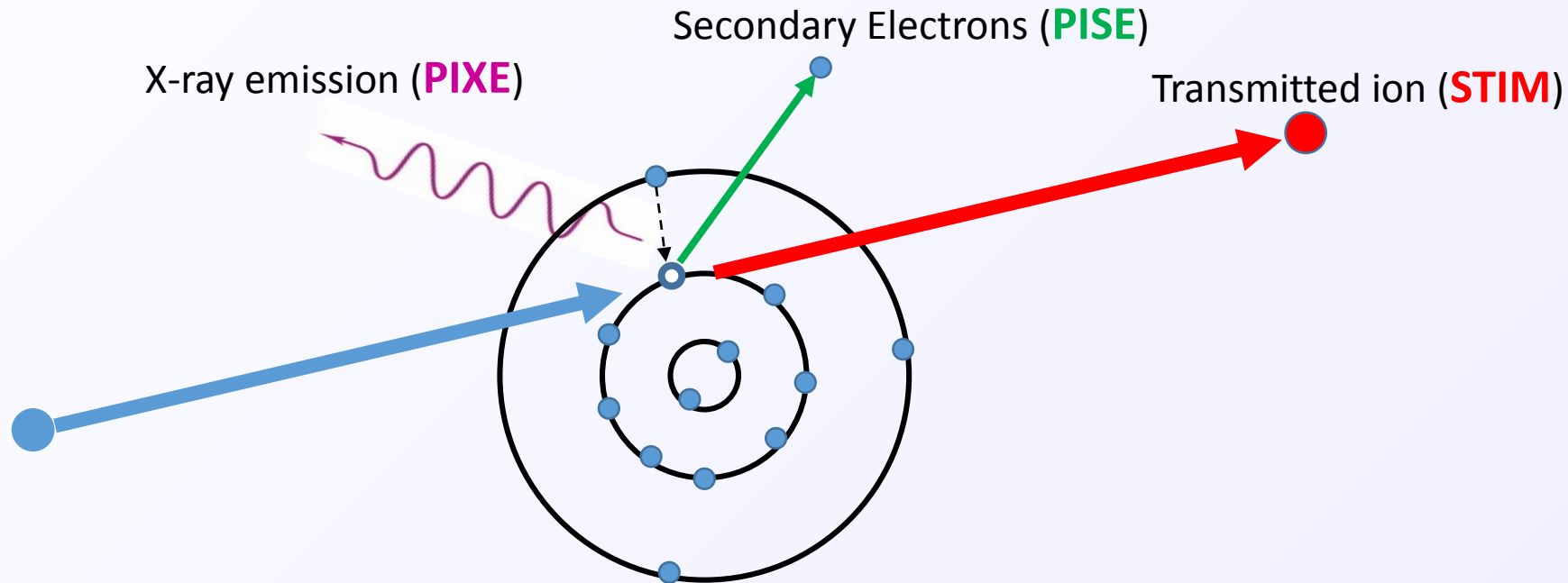
Ion-solid interaction

For Ion Beam Analysis, interactions between the ion probe and atomic electrons are much more probable than with atomic nuclei

Electronic energy loss provides a higher rate of signals

Different electronic processes

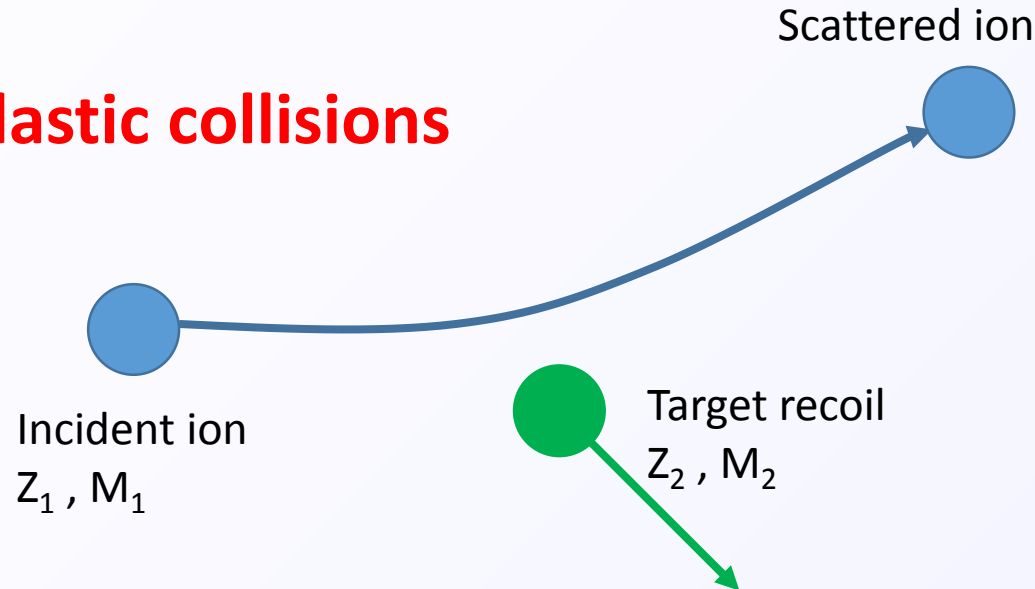
For Example



Nuclear Energy Loss

Typically, the energy lost by ^1H and ^4He MeV ions in collisions with atomic nuclei is less than 10 keV.

Elastic collisions



Screened Coulomb Potential

$$V(r) = Z_1 \cdot Z_2 \frac{e^2}{4\pi\epsilon_0 r} \chi(r)$$

First terms: **Coulomb potential** for two bare nuclei with charges eZ_1 and eZ_2 .

χ : screening function

(for high energy ions, i.e. Rutherford model, : $\chi=1$)

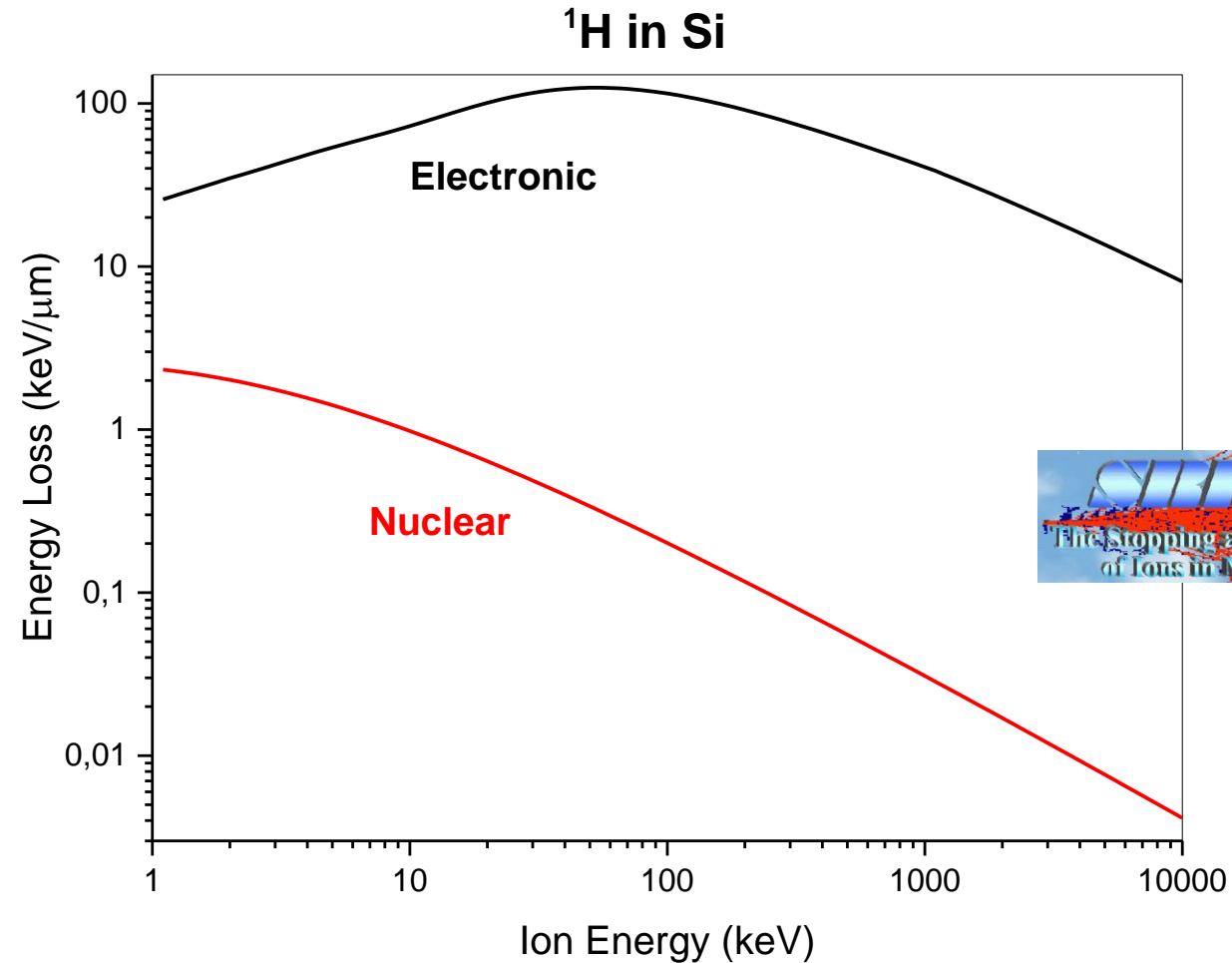
Ziegler-Biersack-Littmark (ZBL) Universal potential

χ Can be determined from fitting simulations of interatomic potentials for different Z_1 and Z_2 combinations

$$\chi(x) = \sum_{i=1}^4 a_i e^{-b_i x}$$

Thomas-Fermi
Screening radius

with $x = \frac{r_{12}}{a_u}$ and $a_u = \frac{0.885 \cdot a_{Bohr}}{Z_1^{0.23} + Z_2^{0.23}}$



An ion can approach closer to the atomic nucleus with increasing energy and eventually it can approach to within a distance comparable with the nuclear radius
No pure Coulomb potential -> nuclear forces affect the collision

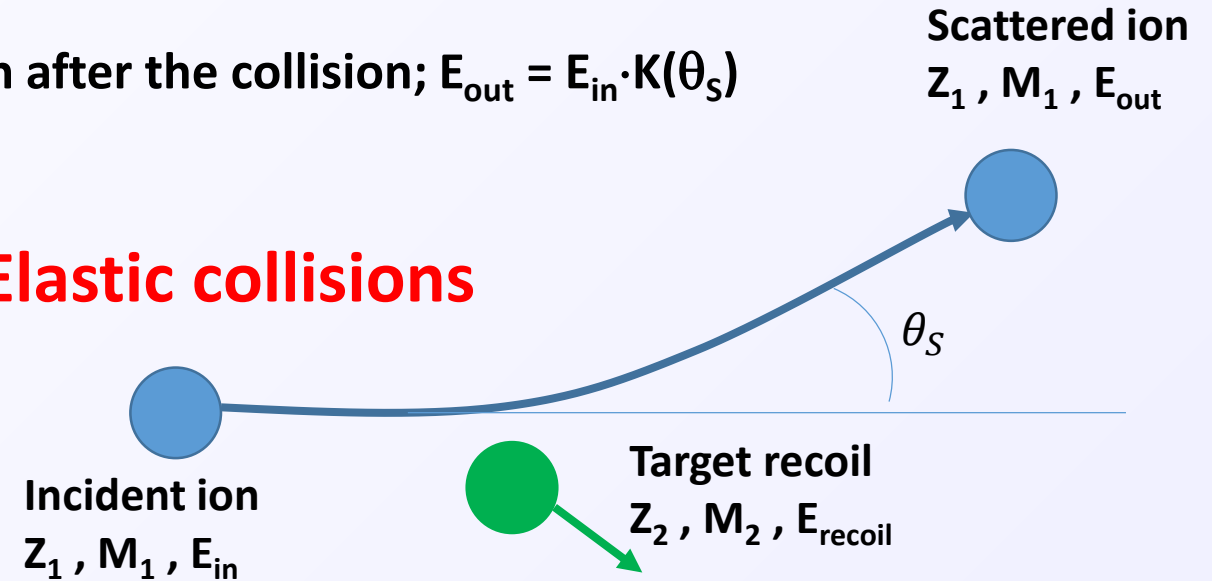
Classical Scattering theory

Fraction of the ion energy which remains with the ion after the collision; $E_{\text{out}} = E_{\text{in}} \cdot K(\theta_s)$

Kinematic factor $K(\theta_s)$; θ_s scattering angle.

Energy of the recoil nucleus: $E_{\text{recoil}} = (1 - K(\theta_s)) \cdot E_{\text{in}}$

Elastic collisions

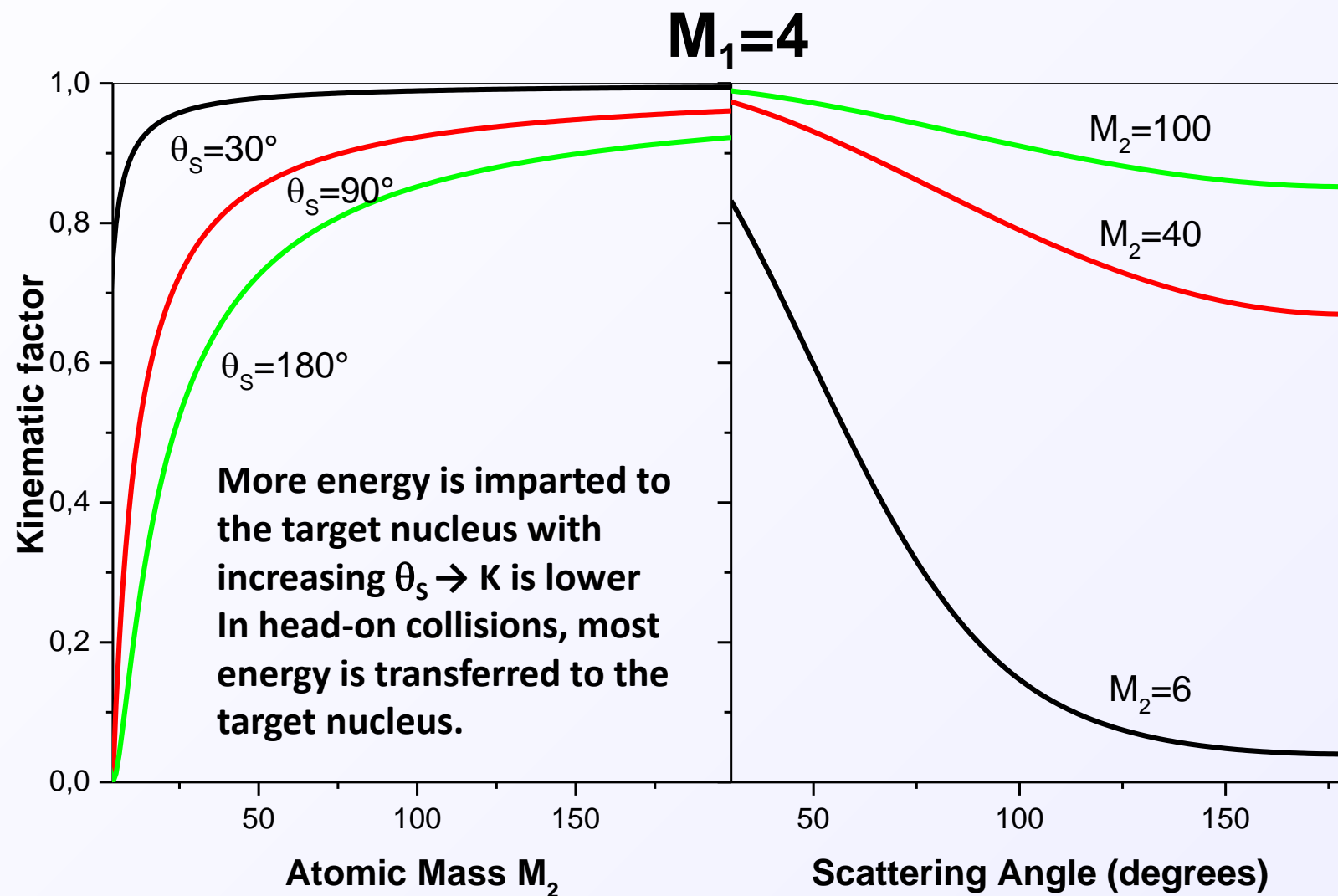


From the conservation of energy and momentum, in non-relativistic form and in the laboratory reference frame:

$$K(\theta_s) = \left\{ \frac{\sqrt{1 - \left(\frac{M_1}{M_2}\right)^2 \cdot \sin^2(\theta_s)} + \left(\frac{M_1}{M_2}\right) \cdot \cos(\theta_s)}{1 + \frac{M_1}{M_2}} \right\}^2$$

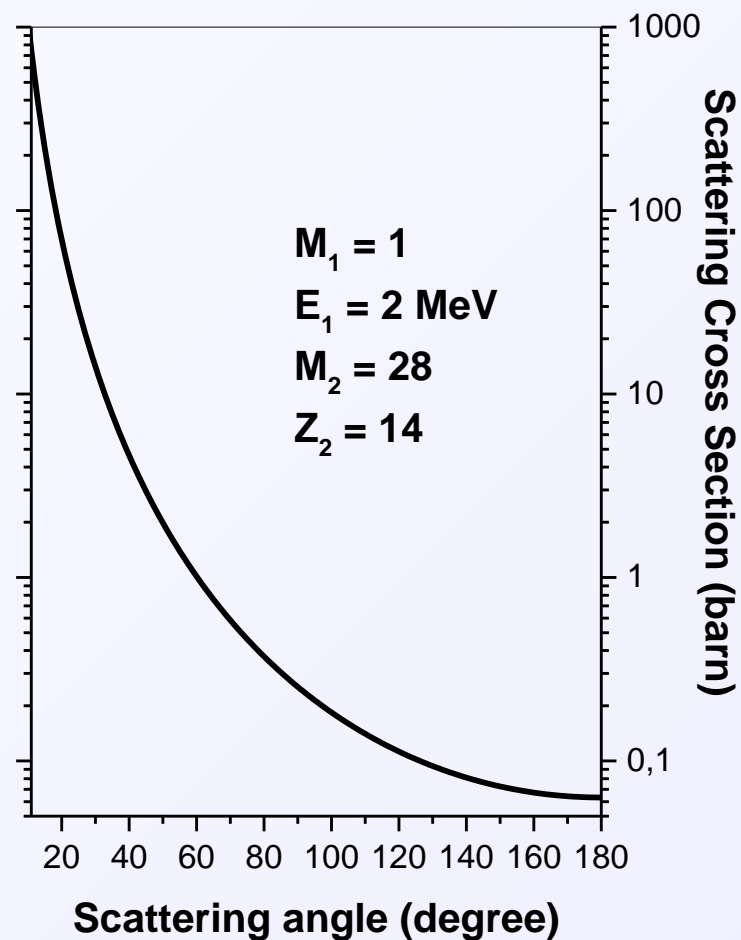
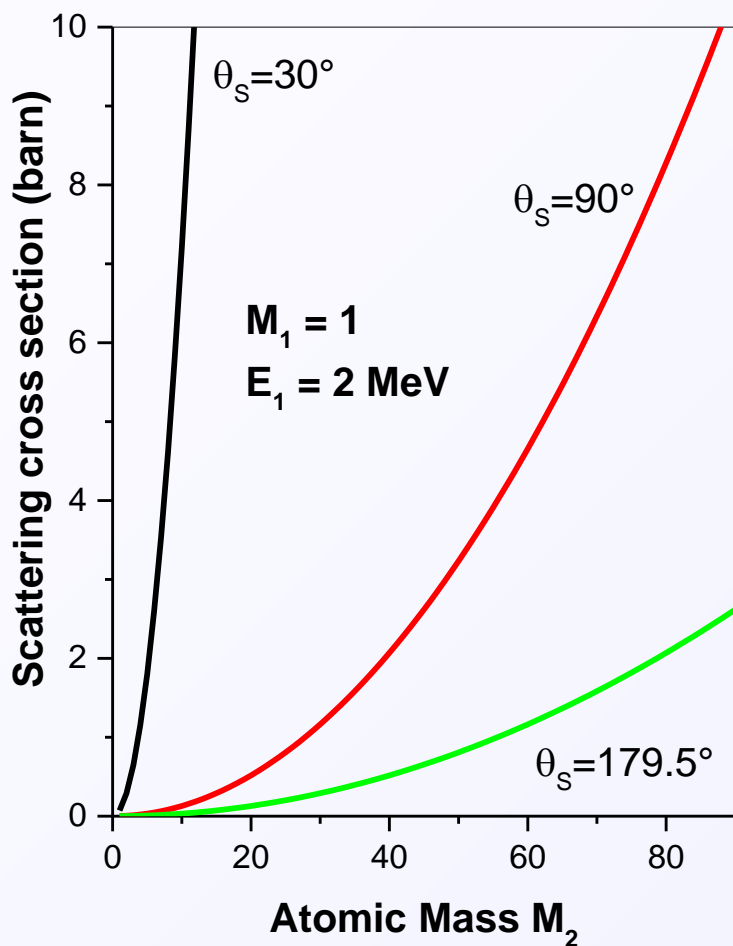
$K(\theta_s)$ depends only on the scattering angle and the ratio of masses of the ion and the atomic nucleus.

It does not depend on the ion energy

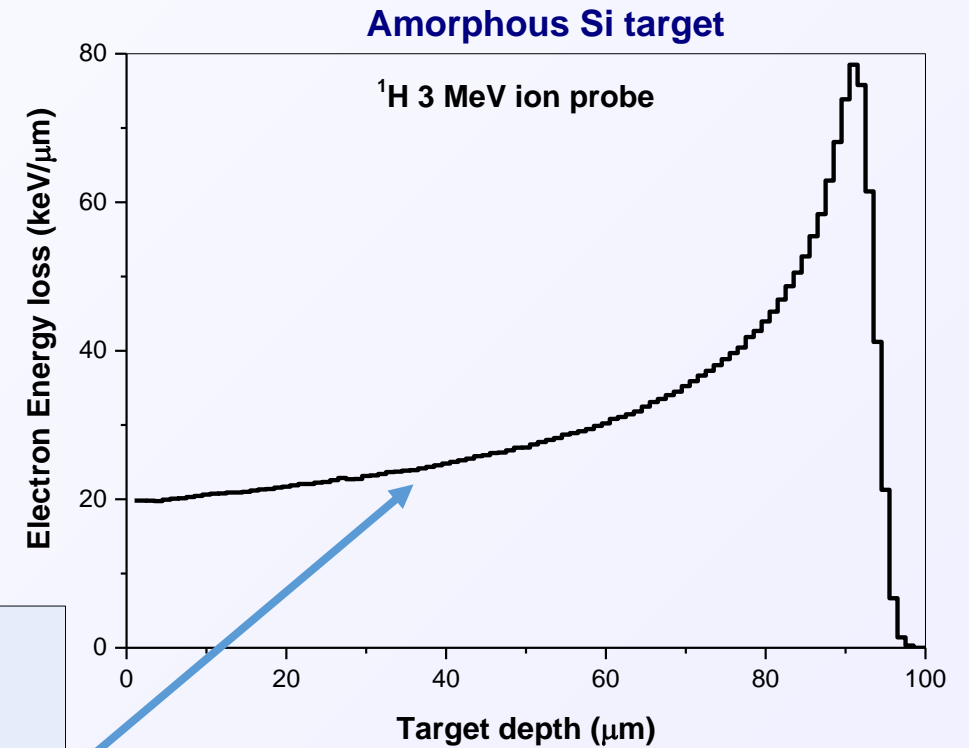
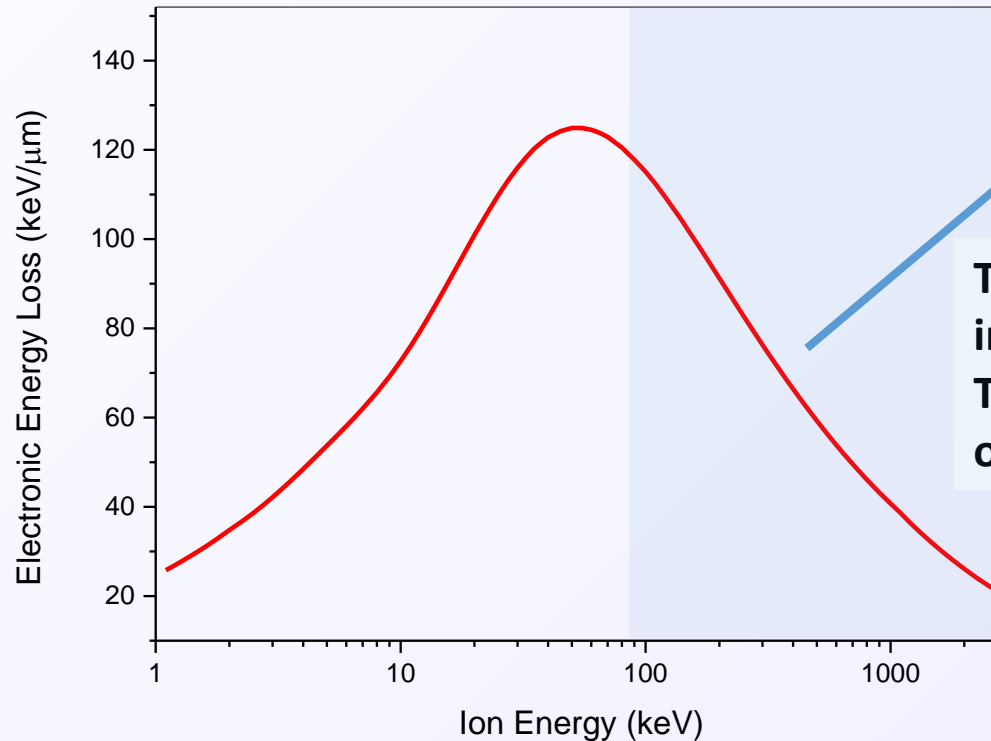


Scattering cross section

Probability of ions being scattered through an angle θ_s
$$\sigma(\theta_s) = \left[\frac{e^2}{4 \cdot \epsilon_0} \cdot \frac{Z_1 \cdot Z_2}{4 \cdot E_{in}} \right]^2 \cdot \left\{ \frac{1}{\sin^4 \left(\frac{\theta_s}{2} \right)} - 2 \left(\frac{M_1}{M_2} \right)^2 \right\}$$

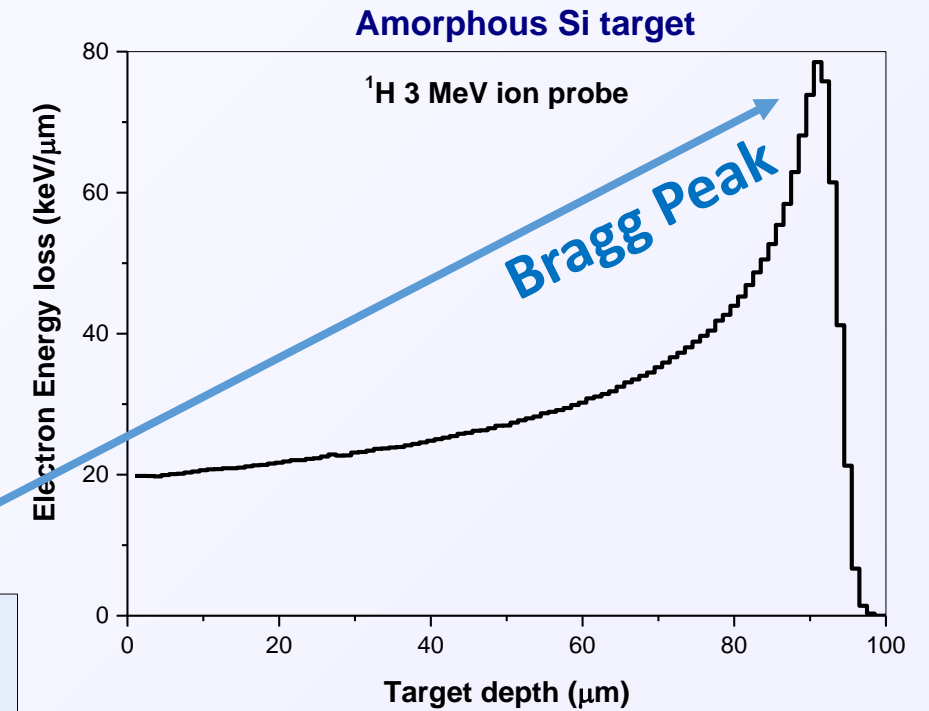
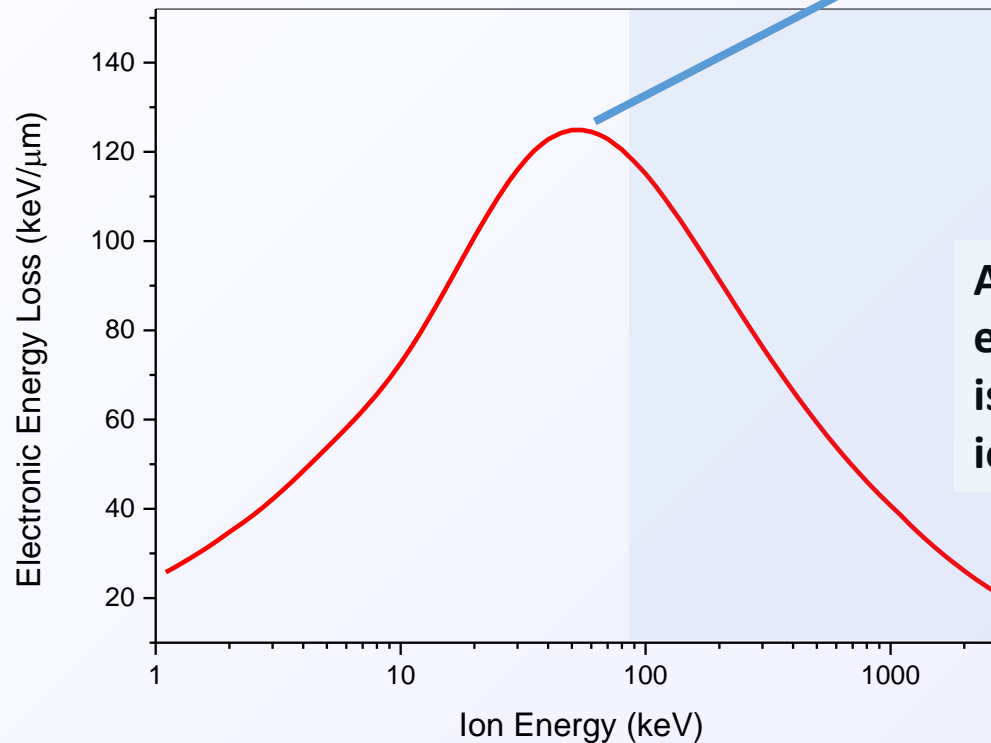


MeV ions continually lose their kinetic energy in collisions mainly with the electrons until they come to rest at some depth within the material.



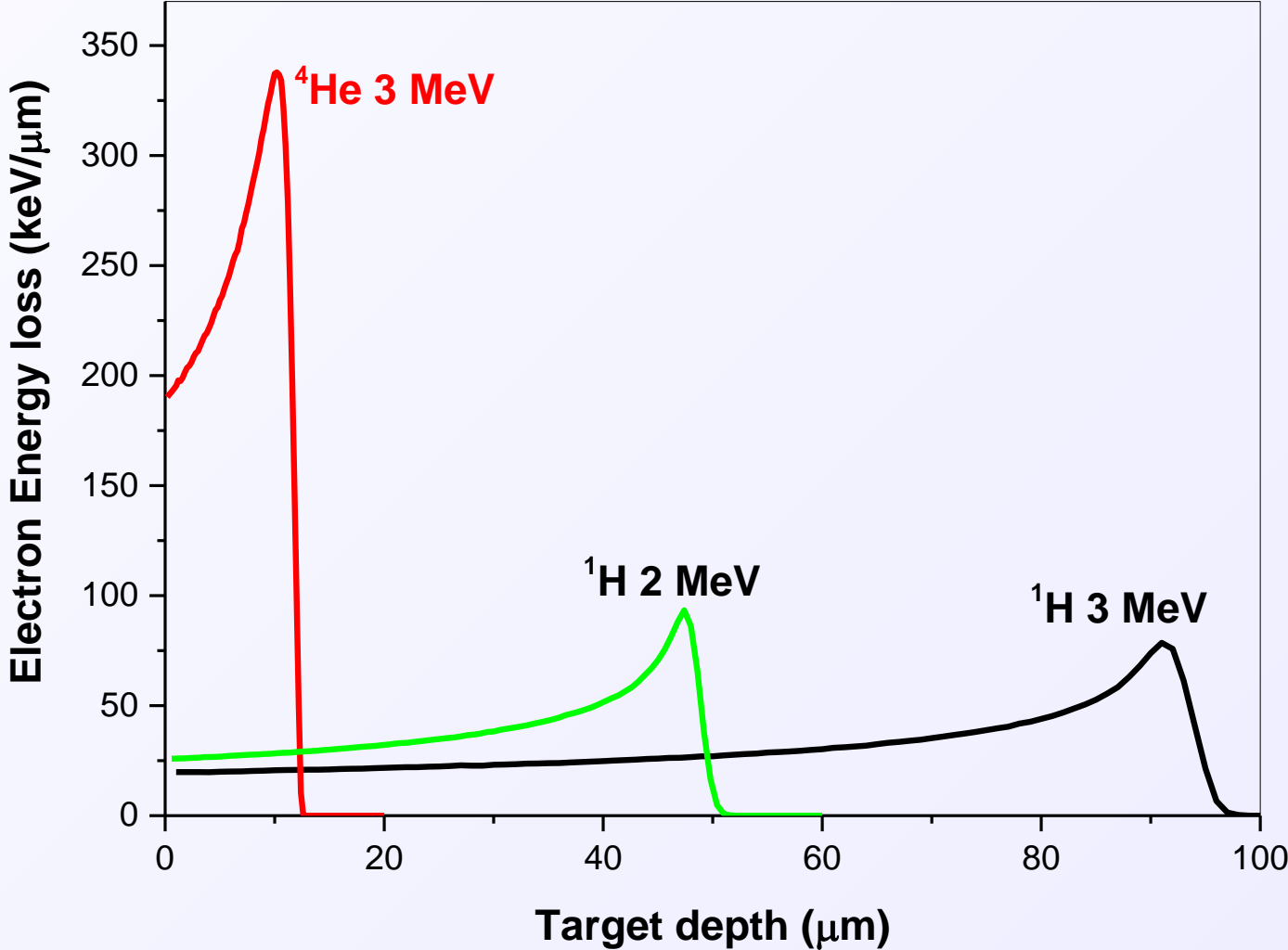
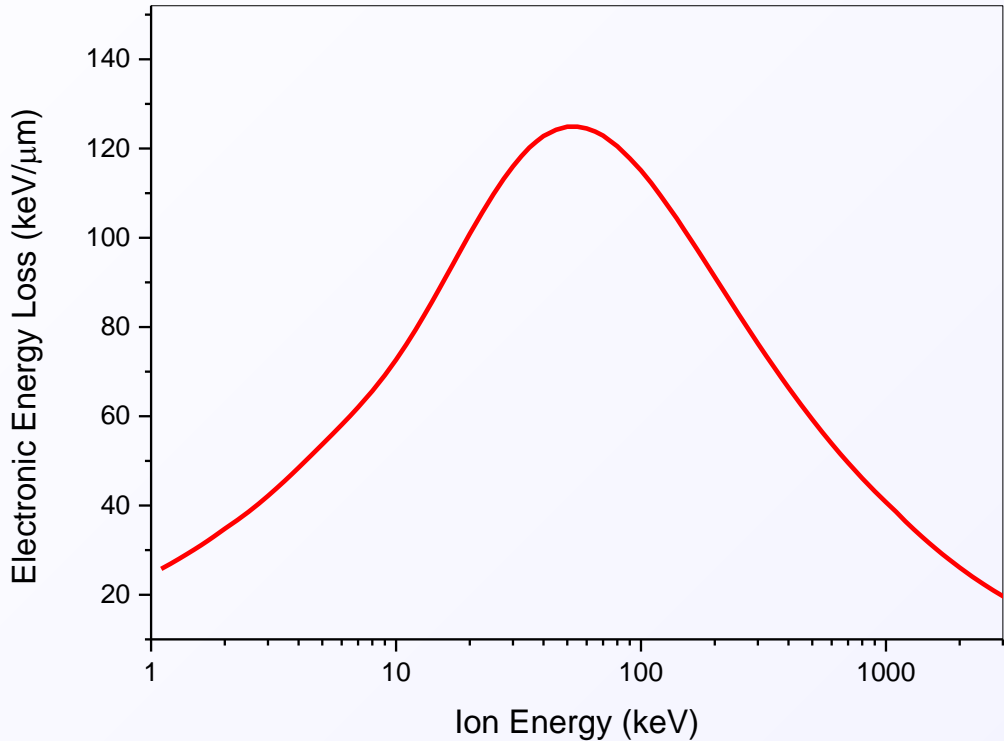
The rate of ion energy loss increases initially as the ion penetrate further
The rate of ion energy loss is to the right of the maximum value

MeV ions continually lose their kinetic energy in collisions mainly with the electrons until they come to rest at some depth within the material.



As the ion penetrate further, the rate of energy loss reaches a maximum, which is close to the end of range for MeV light ions→**BRAGG PEAK**

MeV ions continually lose their kinetic energy in collisions mainly with the electrons until they come to rest at some depth within the material.

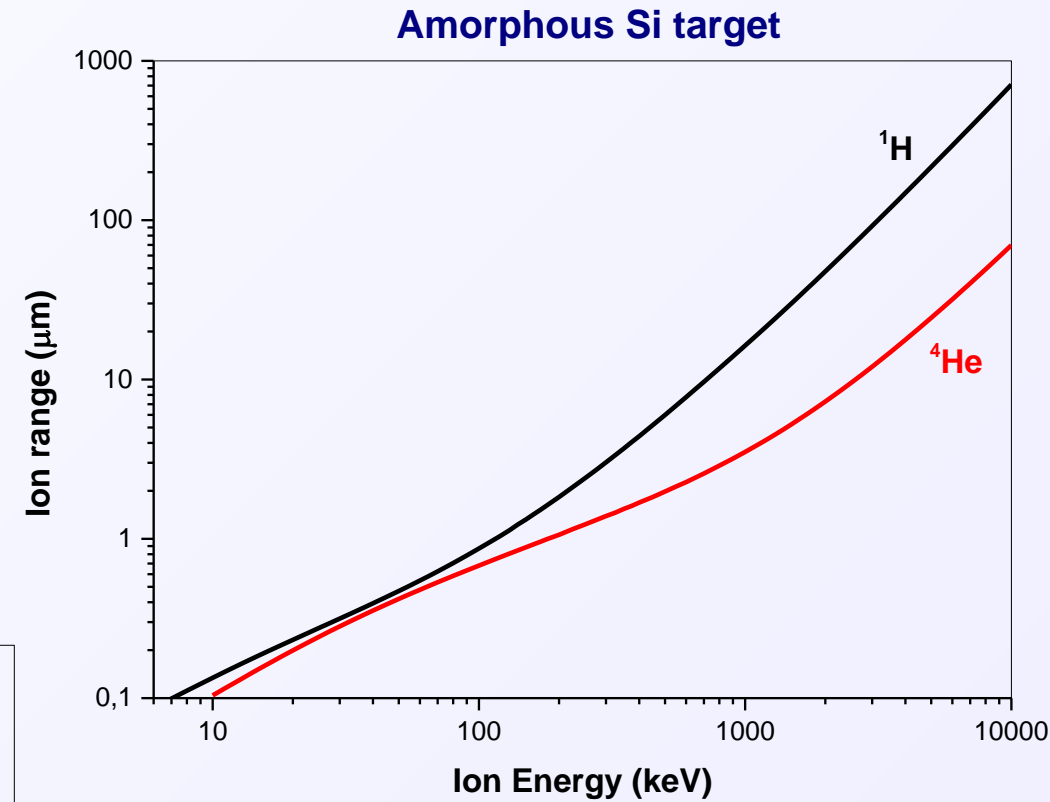
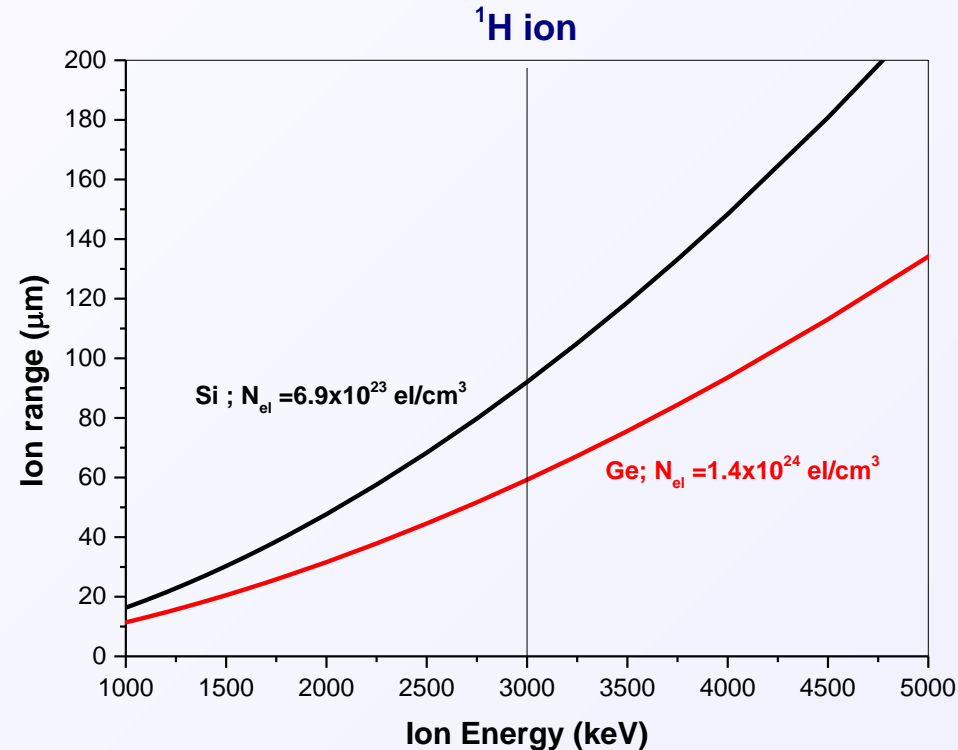


Ion Range

MeV ions continually lose their kinetic energy in collisions mainly with the electrons until they come to rest at some depth within the material.

Ion Range: average range R which MeV light ions travel through matter before coming to rest:

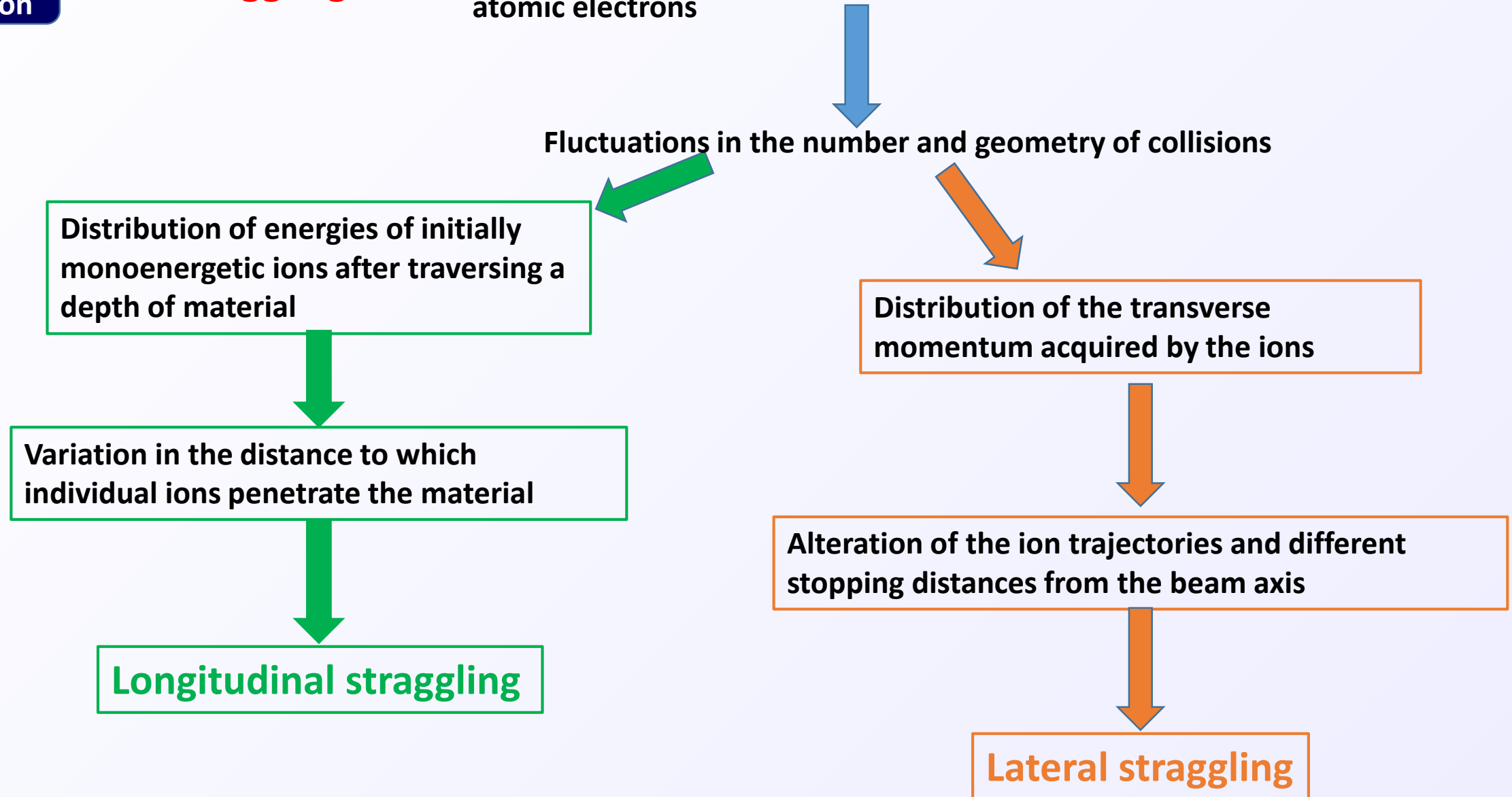
$$R(E_{in}) = \int_0^{E_{in}} \frac{dE}{\left(\frac{dE}{dz}\right)}$$



Ion range is function of energy
Ion range is function of the target density

Ion Straggling

In practice, MeV ions lose their energy in discrete collisions with individual atomic electrons



Ion-solid interaction

Ion Straggling

Mean projected range

$$R_P = \frac{\sum_{i=1}^N x_i}{N} = \langle x \rangle$$

Longitudinal straggling

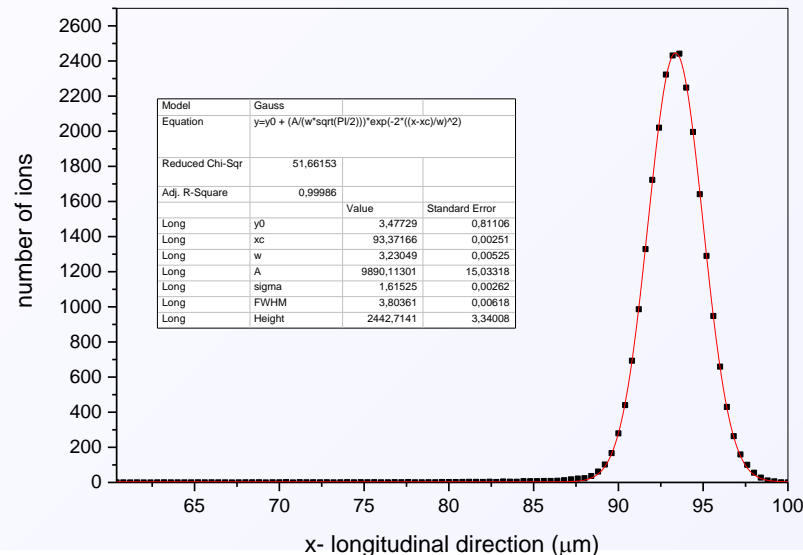
$$\sigma = \sqrt{\langle x^2 \rangle - \langle x \rangle^2}$$

Lateral projected range

$$R_P = \frac{\sum_{i=1}^N y_i}{N} = \langle y \rangle$$

Lateral straggling

$$\sigma_y = \sqrt{\langle y^2 \rangle - \langle y \rangle^2}$$



- analytical models PRAL (Projected Range Algorithm)

J.P. Biersack, NIM 182/183 (1981) 199

J.P. Biersack, Z.Phys. A305 (1982) 95

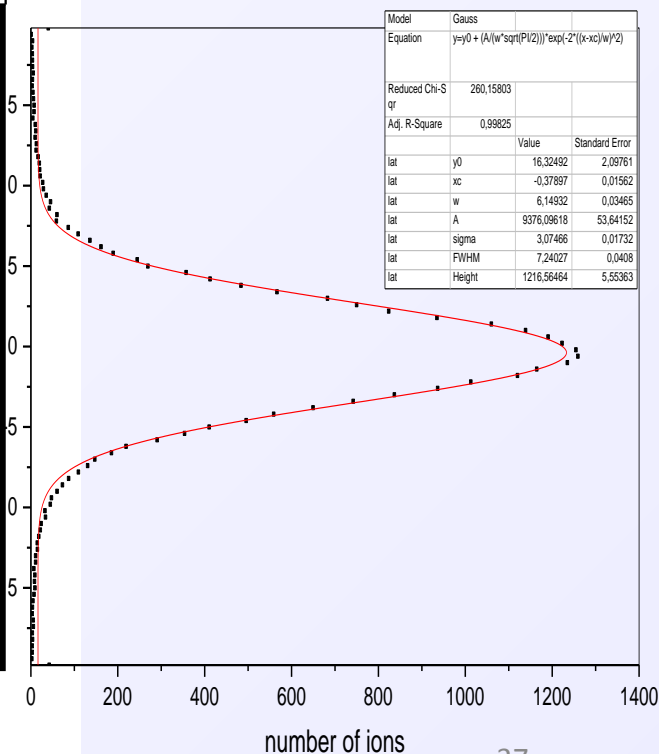
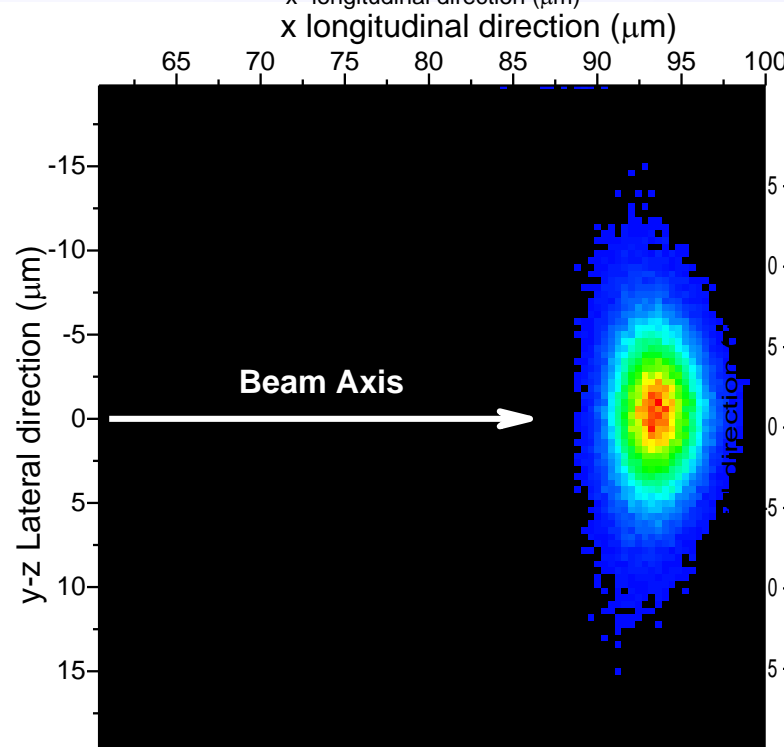
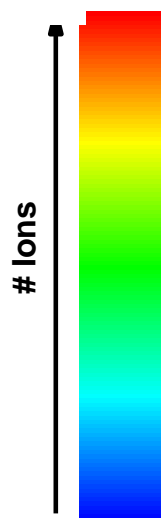
Book by Ziegler, Biersack, Littmark (1985)

- values fitted to experimental data

Gupta & Bhattacharya, Phys. Rev. B29 (1984) 2449

Izsack et al. NIM B15 (1986) 34

Kido et al. NIM B15 (1986) 42



Computer codes for stopping power:

- PSTAR and ASTAR, from NIST, for protons and alphas
<http://physics.nist.gov/PhysRefData/Star/Text/PSTAR.html>
- MSTAR, from IAEA, calculates electronic stopping power for heavy ions (from ^3Li to ^{18}Ar) :
<https://www-nds.iaea.org/stopping/MstarWWW/MSTARInstr.html>
- ATIMA, from GSI, calculates quantities characterizing the slowing down of protons and heavy ions in matter
<https://web-docs.gsi.de/~weick/atima/>
- CasP, from HZB, electronic stopping power of all ions
https://www.helmholtz-berlin.de/people/gregor-schiwietz/casp_en.html

For a critical comparison:

«Judging the reliability of stopping power tables and programs for heavy ions»

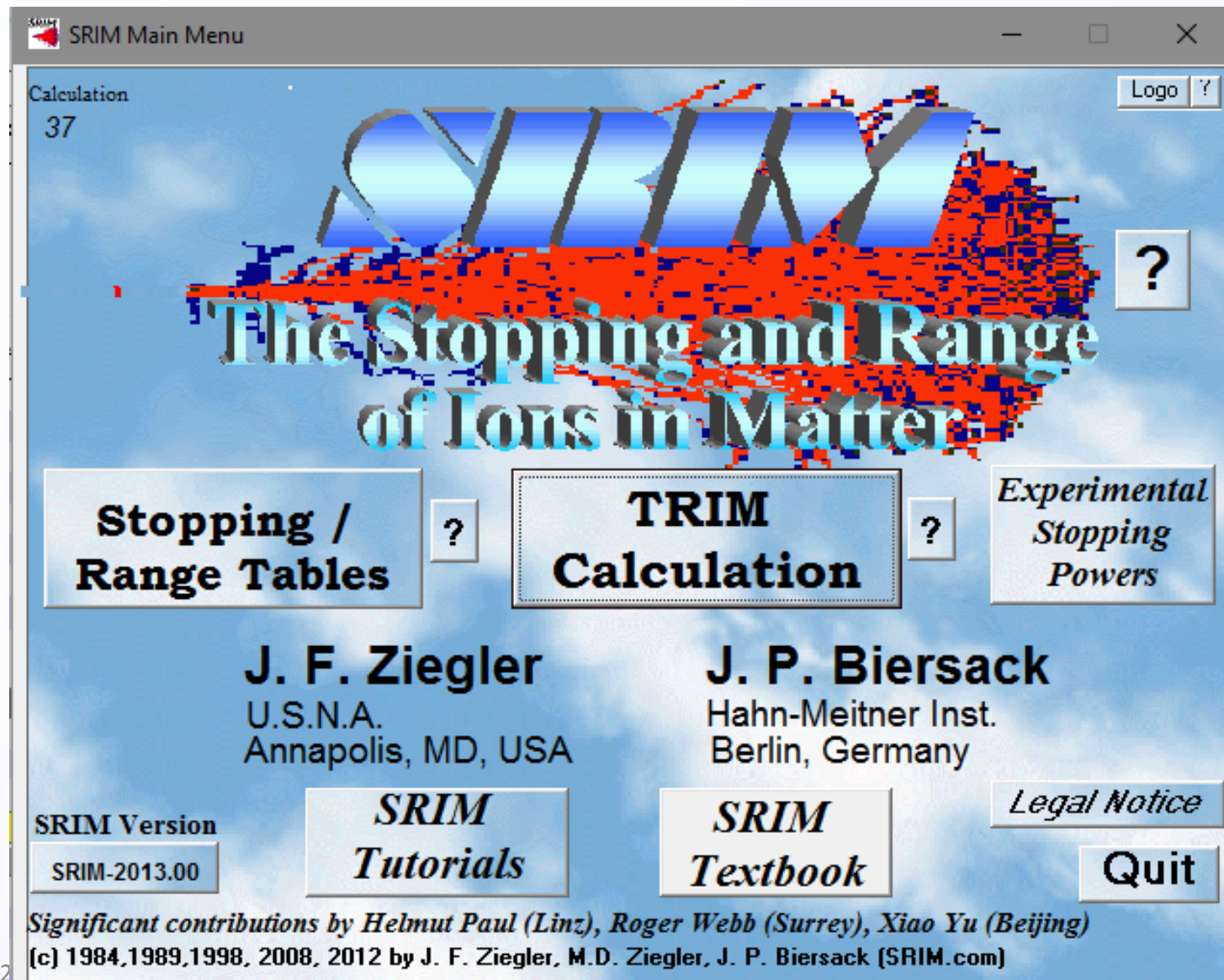
Nucl. Instr. Meth. Phys. Res. B 209 (2003) 252

Simulation codes (Monte Carlo Tracing Techniques) to investigate the interaction and trajectories of fast ions with matter

- **SRIM: The Stopping and Range of Ions in Matter**
www.srim.org
- **CRYSTAL SRIM: For trajectories in crystal lattices**
<https://www.hzdr.de/db/Cms?pOid=21576&pNid=0>
- **GEANT4: (Geometry and Tracking=) is a platform for the simulation of the passage of particles through matter using Monte Carlo methods**
www.geant4.org/geant4
- **MARLOWE: simulates atomic collisions in crystalline targets using the binary collision approximation**
<https://www.oecd-nea.org/tools/abstract/detail/psr-0137>

www.SRIM.org

SRIM is based on a Monte Carlo simulation method, namely the binary collision approximation (BCA) with a random selection of the impact parameter of the next colliding ion. BCA treats interactions as binary collisions and one collision is calculated at a time.



Ion-solid interaction

Stopping Experiment/Theory

Ion = Hydrogen (1)
Target = Silicon (14)

STOP-2011

Data Sets=19 (204pts)
Mean Error= 8.4 o/a

Ion Energy (keV/amu)

Hydrogen Stopping (eV-cm²/10¹⁶)

Ion = Hydrogen (1)
Target = Silicon (14)

STOP-2011 (Solid Line)

Plotted are Ion Names

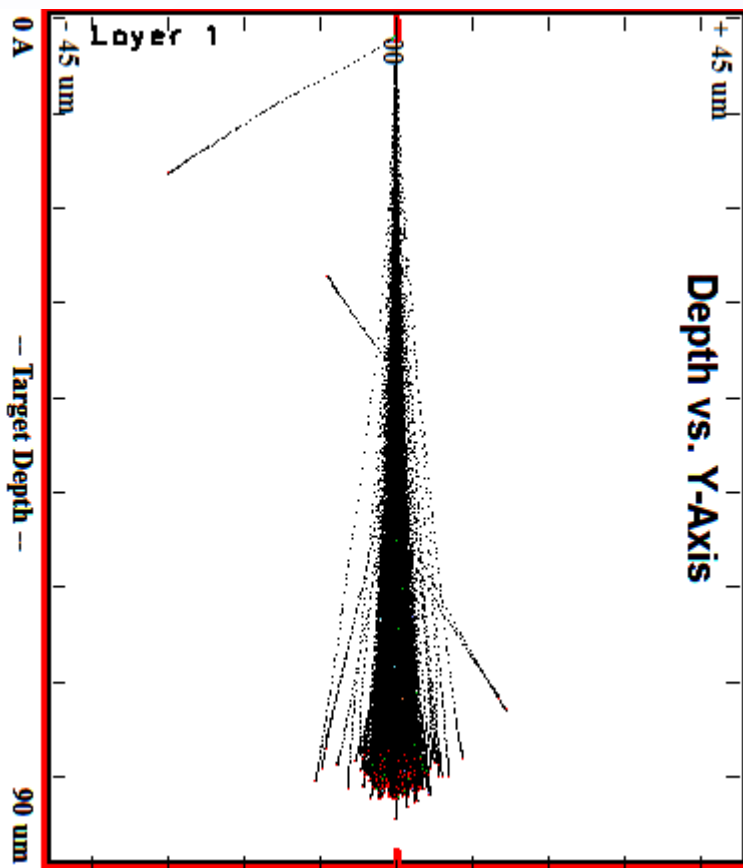
V_F = 0.974
<I> = 171

Data Sets =19 (204pts)
Mean Error = 8.4 o/a

Data Sym	Citation YEAR	Total Points	Pts <1	Pts ≥1	Ref Num
*H	1969	4	4	0	410
*H	1972	4	4	0	486
*H	1976	8	8	0	817
*H	1976	11	11	0	871
*H	1977	25	25	0	1033
*H	1978	11	11	0	1631
*H	1980	11	11	0	1342
*H	1981	21	21	0	1394
*H	1981	13	13	0	1736
*H	1982	10	10	0	1412
*H	1984	7	7	0	1680
*H	1984	5	5	0	1770
*H	1985	12	12	0	1963
*H	1988	13	13	0	1720
*H	1996	10	10	0	1101
*H	1996	7	7	0	2029
*H	2002	7	7	0	3129
*H	2006	8	8	0	3118
*D	1961	19	19	0	1756

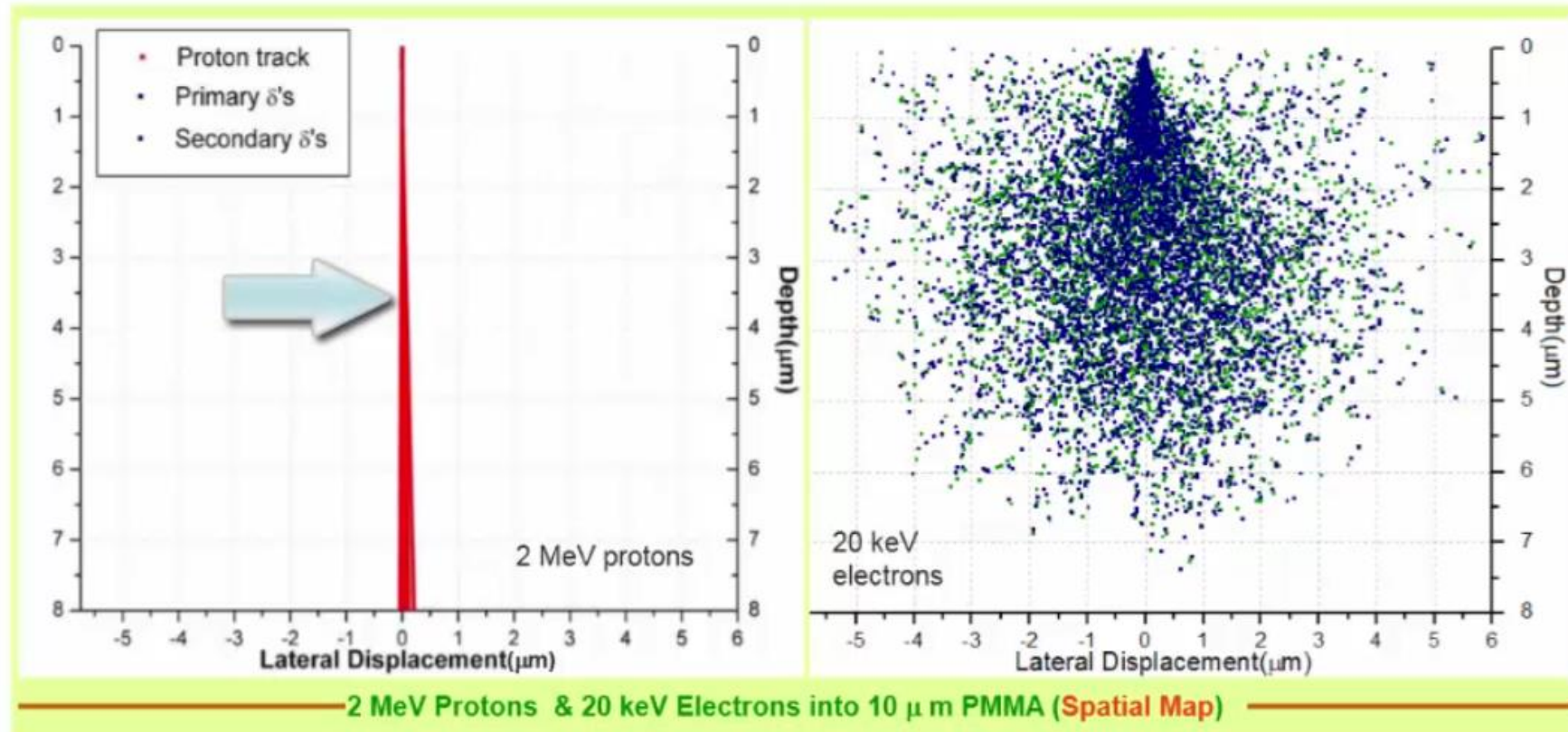
ZPL010/STOP
Apr. 27, 2011

2 MeV ^1H in PMMA



ION STATS	Range	Straggle
Longitudinal	79.3 um	2.53 um
Lateral Proj.	1.44 um	2.17 um
Radial	2.29 um	2.42 um

Comparing P-beam and E-beam trajectories



Red-primary protons: Blue-Primary electrons: Green-secondary electrons



CIBA: Centre for Ion
Beam Applications, Dept
of Physics, NUS.

<http://www.ciba.nus.edu.sg/pages/gallery.html>

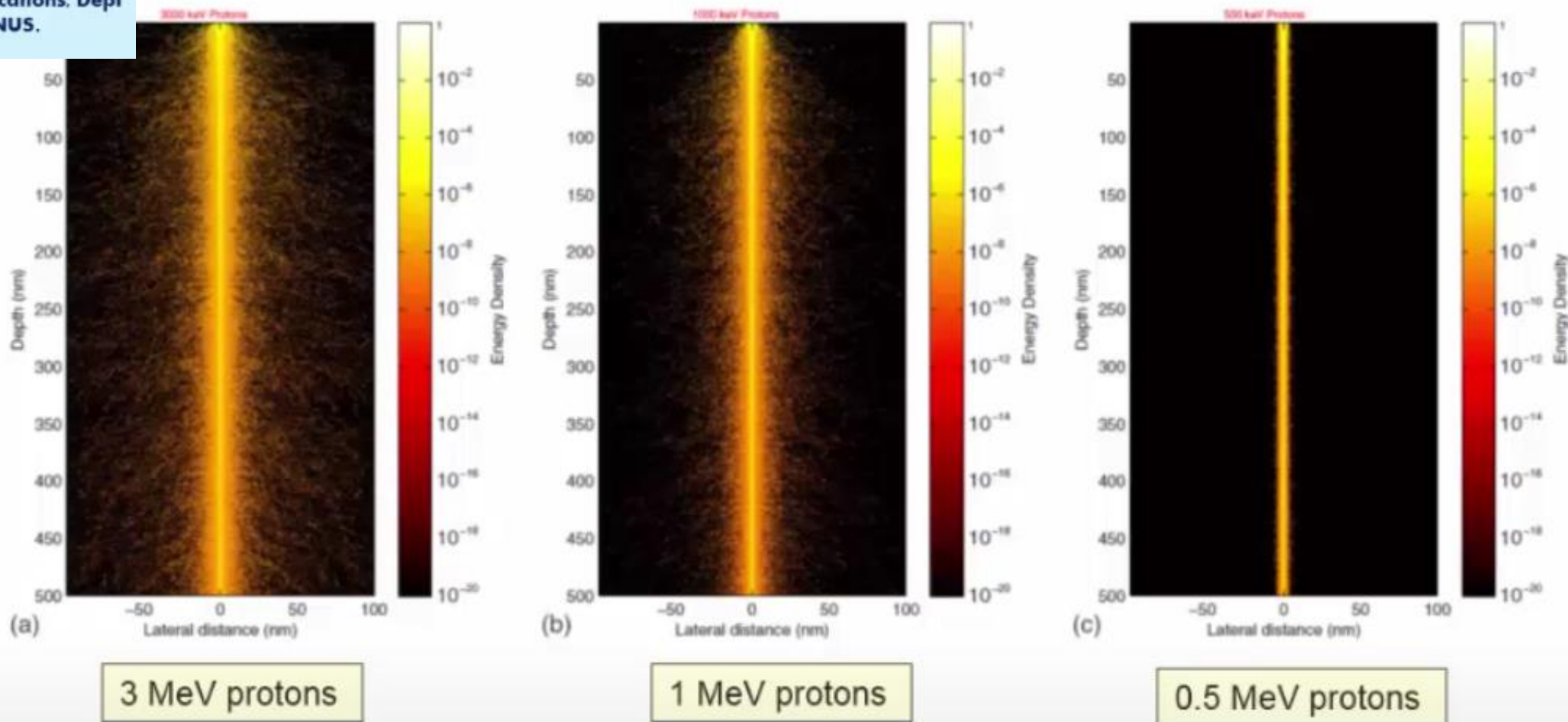
Energy density distributions around the proton tracks: (10,000 protons) calculated using 'DEEP'. Includes secondary electron production energy loss, plasmons, atomic excitation.....



CIBA: Centre for Ion
Beam Applications, Dept
of Physics, NUS.

<http://www.ciba.nus.edu.sg/pages/gallery.html>

Udalagama et al.
Phys.Rev. B80
224107 (2009)

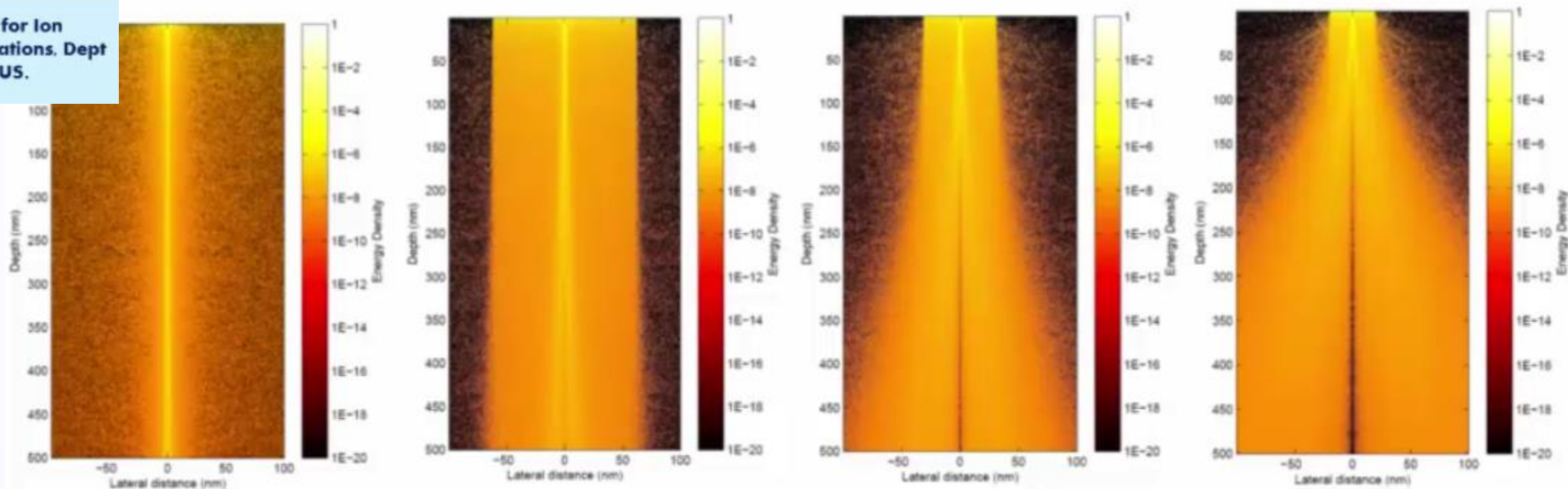


Results show not only a straight path for primary ions, but a highly confined lateral energy deposition in the initial path into organic material.

Energy density distributions (electrons) calculated using 'DEEP'.



CIBA: Centre for Ion
Beam Applications, Dept
of Physics, NUS.



1 MeV electrons*)

100 keV electrons*)

25 keV electrons*)

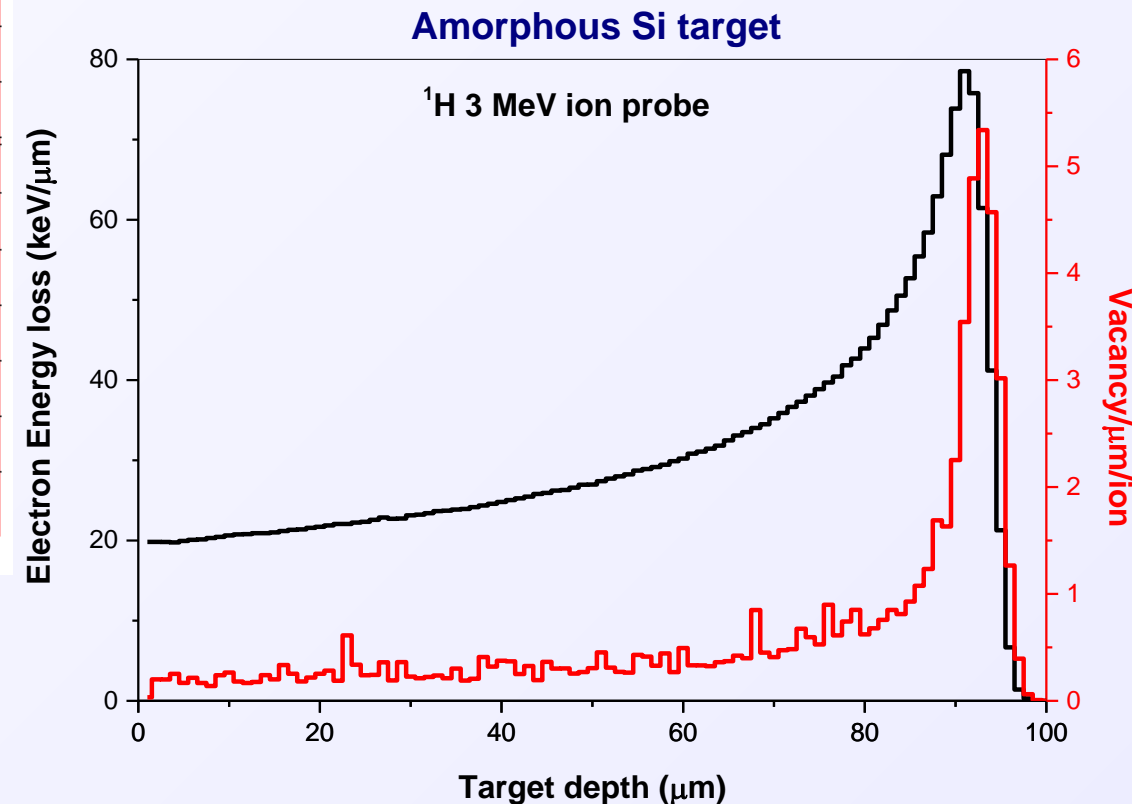
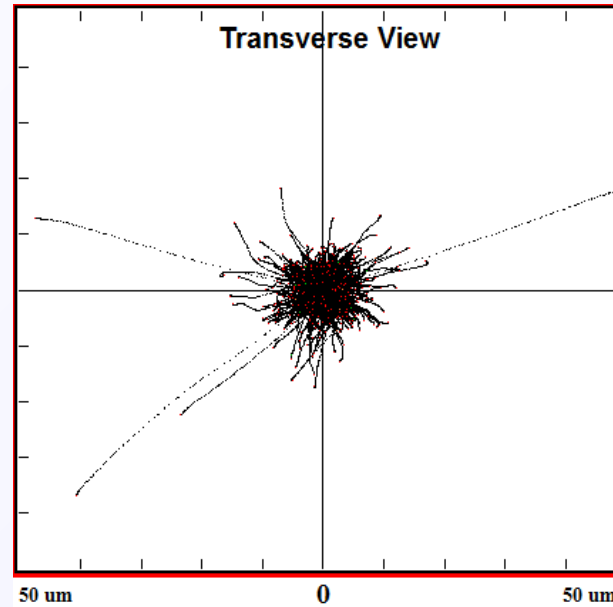
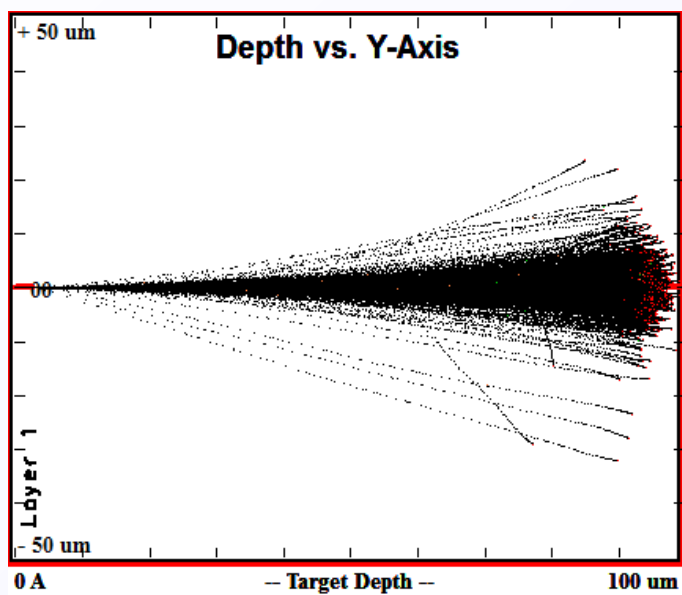
10 keV electrons*)

The lateral energy distribution (proximity effects) is much worse for electrons.

*)The number of electrons have been adjusted to give the same linear energy deposition as 10,000 protons.

Characteristics of MeV ion interaction with matter

- Light MeV ions (^1H , ^4He) maintain a straight path through the sample (unlike electrons), until they reach the end of range. Over the first few micrometers of their trajectory, the ions only diverge few nanometers.
- At the end of range, the energy deposition increases due to nuclear collisions and the ion suffers increased scattering. This can disrupt the position of target atoms, and result in modified electronic, optical and chemical properties in the target.



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www.mrs.org

Mark B. H. Breese, David N. Jamieson, Philip J. C. King

Materials Analysis Using a Nuclear Microprobe

John Wiley & Sons, NY 1996

Webgraphy

WEBINARS @ CENTER FOR ION BEAM APPLICATIONS

(CIBA) NATIONAL UNIVERSITY OF SINGAPORE

www.ciba.nus.edu.sg/pages/gallery.html

Massimo Chiari

Tecniche di Analisi con Fasci di Ioni

www.slideshare.net/max0068/chiari-lezione-su-acceleratori-e-sorgenti-di-ioni-2012

IAEA Accelerator Knowledge Portal

nucleus.iaea.org/sites/accelerators/Pages/default.aspx

IAEA Publications

Instrumentation for PIXE and RBS

http://www-pub.iaea.org/MTCD/Publications/PDF/te_1190_prn.pdf

ICTP lectures: M. Mayer

Rutherford Backscattering Spectrometry (RBS)

http://users.ictp.it/~pub_off/lectures/Ins022/Mayer_1/Mayer_1.pdf